

MSP-EXP430G2 LaunchPad Overview

1.2 Features

MSP-EXP430G2 LaunchPad features:

- USB debugging and programming interface featuring a driverless installation and application UART serial communication with up to 9600 Baud
- Supports MSP430G2xx2, MSP430G2xx3, and MSP430F20xx devices in PDIP14 or PDIP20 packages (see Section 4.7 for a complete list of supported devices)
- Two general-purpose digital I/O pins connected to green and red LEDs for visual feedback
- Two push button for user feedback and device reset
- Easily accessible device pins for debugging purposes or as socket for adding customized extension boards
- High-quality 20-pin DIP socket for an easy plug-in or removal of the target device

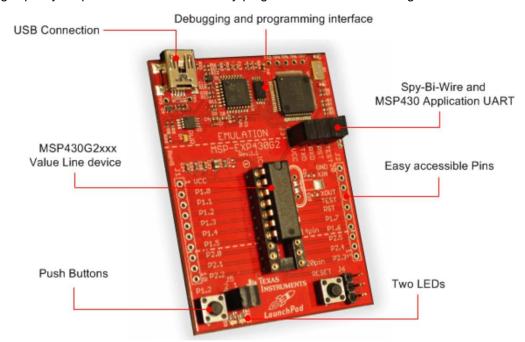


Figure 1. MSP-EXP430G2 LaunchPad Overview

1.3 Kit Contents

The MSP-EXP430G2 evaluation kit includes the following hardware:

- LaunchPad emulator socket board (MSP-EXP430G2)
- Mini USB-B cable, 0.5 m
- Two MSP430 flash devices
 - MSP430G2553: Low-power 16-bit MSP430 microcontroller with an 8-channel 10-bit ADC, on-chip comparator, touch-sense enabled I/Os, universal serial communication interface, 16kB flash memory, and 512 bytes of RAM (preloaded with a sample program)
 - MSP430G2452: Low-power 16-bit MSP430 microcontroller with an 8-channel 10-bit ADC, on-chip comparator, touch-sense enabled I/Os, universal serial interface, 8kB flash memory, and 256 bytes of SRAM
- Two 10-pin PCB connectors female
- 32.768-kHz clock crystal from Micro Crystal (http://www.microcrystal.com)
- Quick start guide
- Two LaunchPad stickers



4.8 MSP-EXP430G2 On-Board Emulator

The MSP-EXP430G2 on-board emulator enables programming and debugging of supported MSP430 devices (see Section 4.7). It offers several features that are enabled by a 2-wire JTAG interface called Spy-Bi-Wire. For a more feature-complete emulator, the MSP-FET430UIF flash emulation tool may be more appropriate. See Table 4 for more details on the MSP-EXP430G2 LaunchPad on-board emulator.

Table 4. Features Supported by On-Board Emulator

Feature	Support by LaunchPad (MSP-EXP430G2)
Supports MSP430F20xx, F21x2, F22xx, G2x01, G2x11, G2x21, G2x31, G2x53	✓
Allows fuse blow	
Adjustable target supply voltage	
Fixed 2.8-V target supply voltage	
Fixed 3.6-V target supply voltage	✓
4-wire JTAG	
2-wire JTAG	✓
Application UART	✓
Supported by CCS	✓
Supported by IAR	✓

5 MSP-EXP430G2 Hardware

5.1 Device Pinout

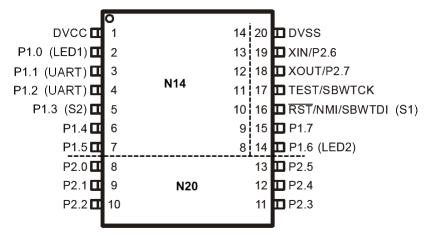


Figure 5. Device Pinout



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5.2 Schematics

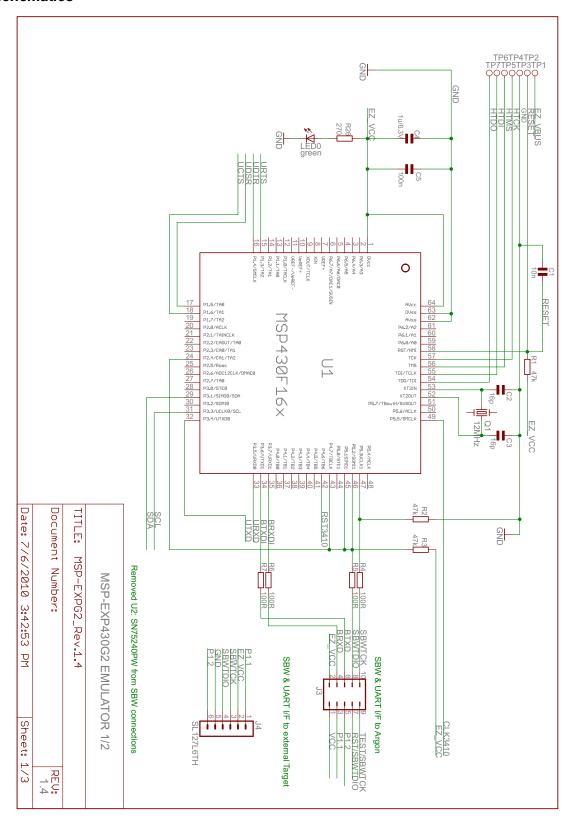


Figure 6. Schematics, MSP-EXP430G2 Emulator (1 of 2), Revision 1.4



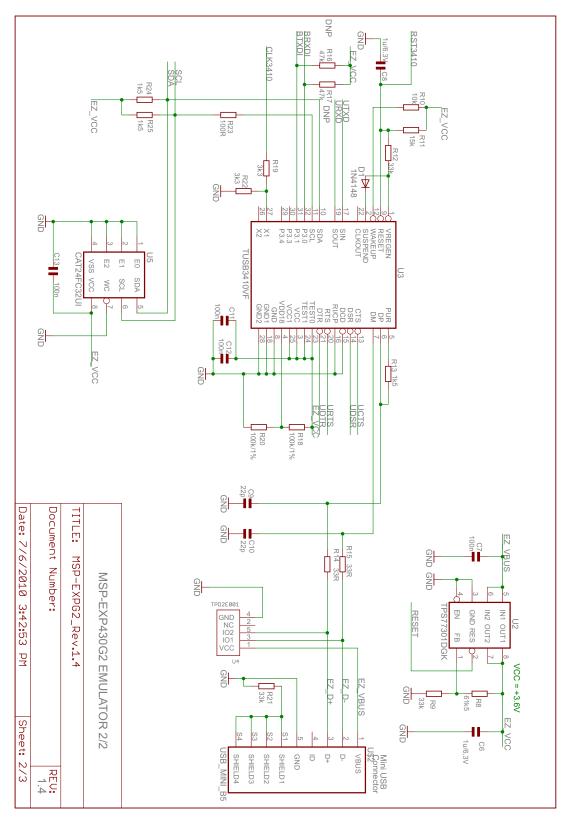


Figure 7. Schematics, MSP-EXP430G2 Emulator (2 of 2), Revision 1.4



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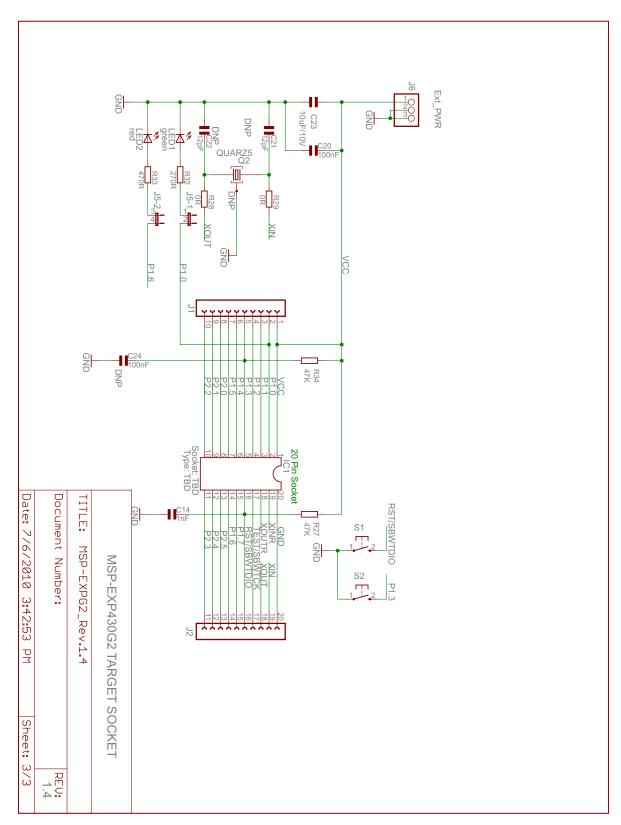


Figure 8. Schematics, MSP-EXP430G2 Target Socket, Revision 1.4



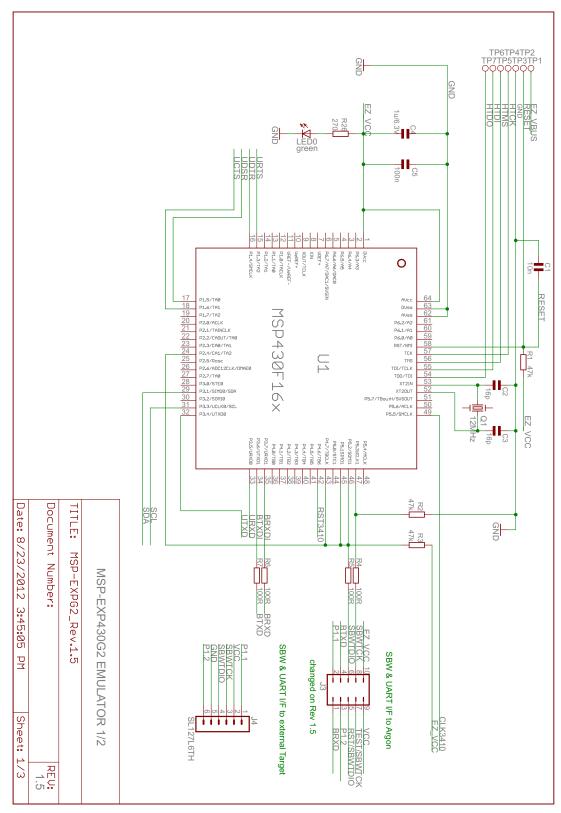


Figure 9. Schematics, MSP-EXP430G2 Emulator (1 of 2), Revision 1.5



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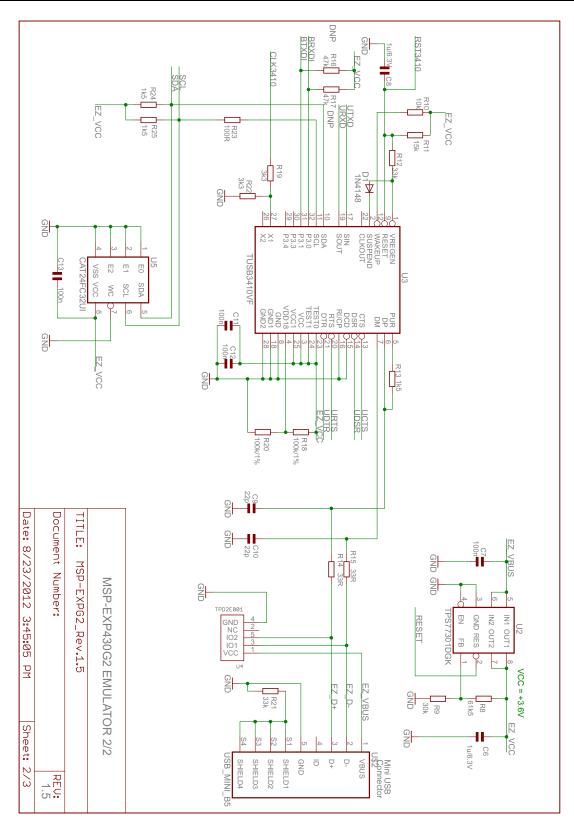


Figure 10. Schematics, MSP-EXP430G2 Emulator (2 of 2), Revision 1.5



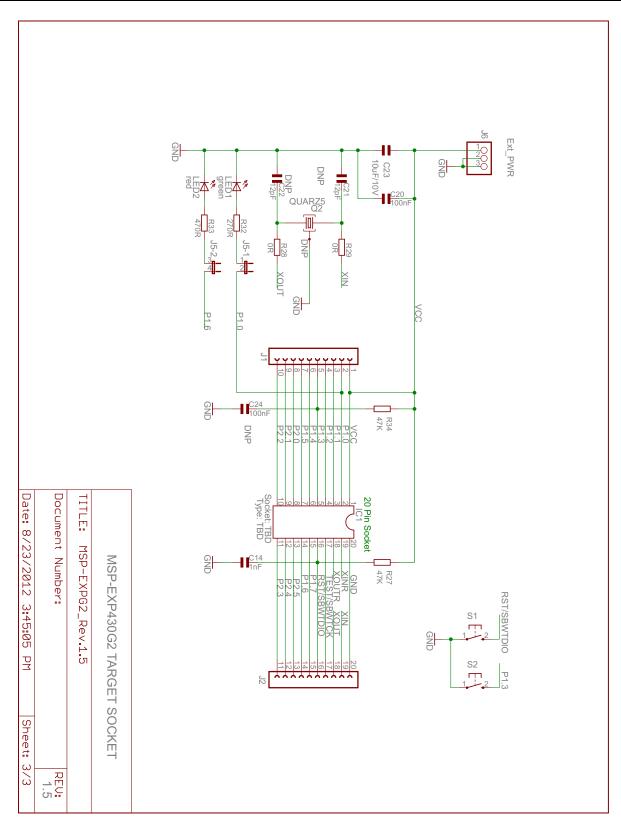


Figure 11. Schematics, MSP-EXP430G2 Target Socket, Revision 1.5

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MIXED SIGNAL MICROCONTROLLER

FEATURES

- · Low Supply-Voltage Range: 1.8 V to 3.6 V
- Ultra-Low Power Consumption
 - Active Mode: 230 μ A at 1 MHz, 2.2 V
 - Standby Mode: 0.5 μA
 - Off Mode (RAM Retention): 0.1 μ A
- Five Power-Saving Modes
- Ultra-Fast Wake-Up From Standby Mode in Less Than 1 µs
- 16-Bit RISC Architecture, 62.5-ns Instruction Cycle Time
- Basic Clock Module Configurations
 - Internal Frequencies up to 16 MHz With Four Calibrated Frequency
 - Internal Very-Low-Power Low-Frequency (LF) Oscillator
 - 32-kHz Crystal
 - External Digital Clock Source
- Two 16-Bit Timer_A With Three Capture/Compare Registers
- Up to 24 Capacitive-Touch Enabled I/O Pins

- Universal Serial Communication Interface (USCI)
 - Enhanced UART Supporting Auto Baudrate Detection (LIN)
 - IrDA Encoder and Decoder
 - Synchronous SPI
 - I²C™
- On-Chip Comparator for Analog Signal Compare Function or Slope Analog-to-Digital (A/D) Conversion
- 10-Bit 200-ksps Analog-to-Digital (A/D)
 Converter With Internal Reference, Sample-and-Hold, and Autoscan (See Table 1)
- Brownout Detector
- Serial Onboard Programming,
 No External Programming Voltage Needed,
 Programmable Code Protection by Security
- On-Chip Emulation Logic With Spy-Bi-Wire Interface
- Family Members are Summarized in Table 1
- · Package Options
 - TSSOP: 20 Pin, 28 Pin
 - PDIP: 20 PinQFN: 32 Pin
- For Complete Module Descriptions, See the MSP430x2xx Family User's Guide (SLAU144)

DESCRIPTION

The Texas Instruments MSP430 family of ultra-low-power microcontrollers consists of several devices featuring different sets of peripherals targeted for various applications. The architecture, combined with five low-power modes, is optimized to achieve extended battery life in portable measurement applications. The device features a powerful 16-bit RISC CPU, 16-bit registers, and constant generators that contribute to maximum code efficiency. The digitally controlled oscillator (DCO) allows wake-up from low-power modes to active mode in less than 1 μ s.

The MSP430G2x13 and MSP430G2x53 series are ultra-low-power mixed signal microcontrollers with built-in 16-bit timers, up to 24 I/O capacitive-touch enabled pins, a versatile analog comparator, and built-in communication capability using the universal serial communication interface. In addition the MSP430G2x53 family members have a 10-bit analog-to-digital (A/D) converter. For configuration details see Table 1.

Typical applications include low-cost sensor systems that capture analog signals, convert them to digital values, and then process the data for display or for transmission to a host system.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



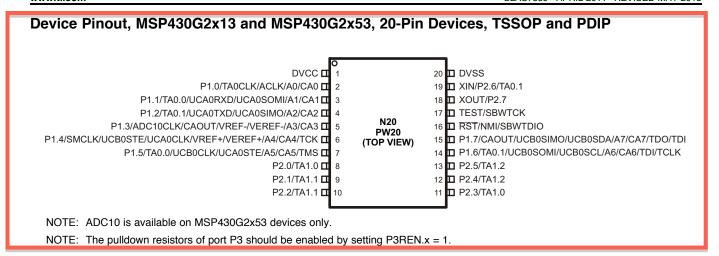
Table 1. Available Options (1)(2)

Tuble 1. Available Options											
Device	BSL	EEM	Flash (KB)	RAM (B)	Timer_A	COMP_A+ Channel	ADC10 Channel	USCI_A0, USCI_B0	Clock	I/O	Package Type
MSP430G2553IRHB32										24	32-QFN
MSP430G2553IPW28	1	1	16	512	2x TA3	8	8	1	LF, DCO,	24	28-TSSOP
MSP430G2553IPW20	'	'	10	312	2X 1A3	0	0	ı.	VLO	16	20-TSSOP
MSP430G2553IN20										16	20-PDIP
MSP430G2453IRHB32										24	32-QFN
MSP430G2453IPW28	1	1	8	512	2x TA3	8	8	1	LF,	24	28-TSSOP
MSP430G2453IPW20	'	'	8	512		8		'	DCO, VLO	16	20-TSSOP
MSP430G2453IN20										16	20-PDIP
MSP430G2353IRHB32										24	32-QFN
MSP430G2353IPW28	1	1	4	256	2x TA3	8	8	4	LF,	24	28-TSSOP
MSP430G2353IPW20	'	'	4	250	2X 1A3	8	0	1	DCO, VLO	16	20-TSSOP
MSP430G2353IN20										16	20-PDIP
MSP430G2253IRHB32										24	32-QFN
MSP430G2253IPW28		1	2	256	2x TA3	8	8	1	LF, DCO, VLO	24	28-TSSOP
MSP430G2253IPW20	1	'	2			0	0			16	20-TSSOP
MSP430G2253IN20										16	20-PDIP
MSP430G2153IRHB32					2x TA3					24	32-QFN
MSP430G2153IPW28	1	1	1	256		8	8	1	LF, DCO,	24	28-TSSOP
MSP430G2153IPW20	'		'			0	0	·	VLO	16	20-TSSOP
MSP430G2153IN20										16	20-PDIP
MSP430G2513IRHB32								1	LF, DCO, VLO	24	32-QFN
MSP430G2513IPW28	1	1	16	512	2x TA3	8	-			24	28-TSSOP
MSP430G2513IPW20	'	'	10							16	20-TSSOP
MSP430G2513IN20										16	20-PDIP
MSP430G2413IRHB32										24	32-QFN
MSP430G2413IPW28	1	1	8	512	2x TA3	8		1	LF, DCO,	24	28-TSSOP
MSP430G2413IPW20	'	'	0	312	2X 1A3	0	-	ı.	VLO	16	20-TSSOP
MSP430G2413IN20										16	20-PDIP
MSP430G2313IRHB32										24	32-QFN
MSP430G2313IPW28	1	1	4	256	2x TA3	8		1	LF,	24	28-TSSOP
MSP430G2313IPW20	'	'	4	250	2X 1A3	0	-	ı.	DCO, VLO	16	20-TSSOP
MSP430G2313IN20										16	20-PDIP
MSP430G2213IRHB32										24	32-QFN
MSP430G2213IPW28			0	056	0,, TA0	0			LF,	24	28-TSSOP
MSP430G2213IPW20	1	1	2	256	2x TA3	8	-	1	DCO, VLO	16	20-TSSOP
MSP430G2213IN20										16	20-PDIP

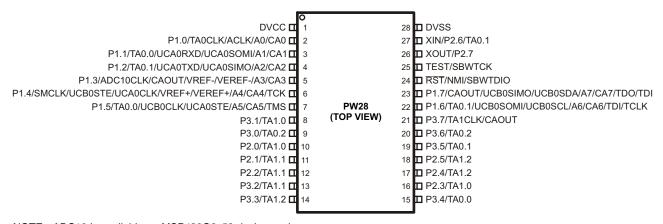
⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

⁽²⁾ Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

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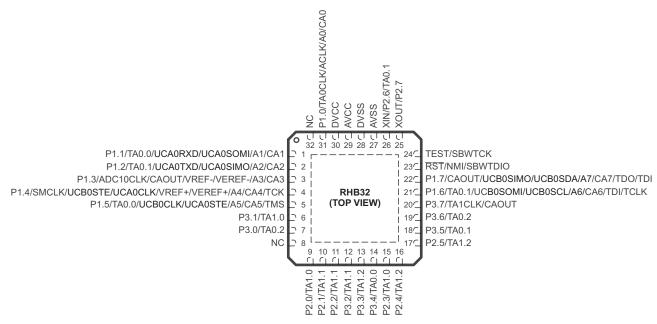
Device Pinout, MSP430G2x13 and MSP430G2x53, 28-Pin Devices, TSSOP



NOTE: ADC10 is available on MSP430G2x53 devices only.

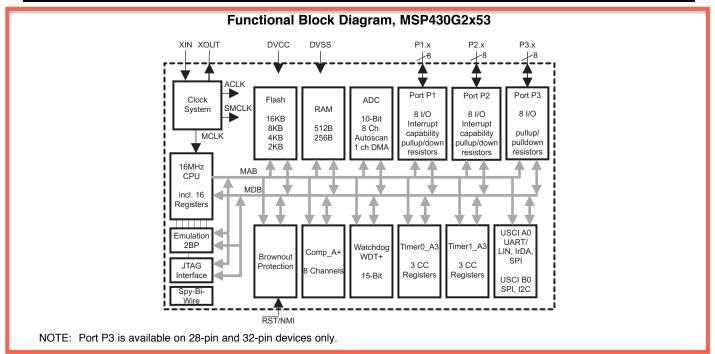


Device Pinout, MSP430G2x13 and MSP430G2x53, 32-Pin Devices, QFN

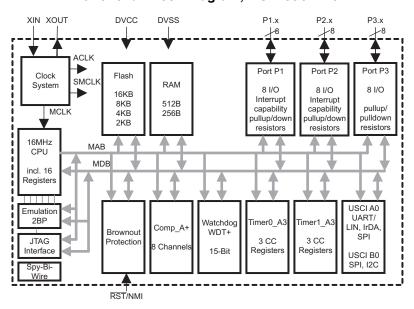


NOTE: ADC10 is available on MSP430G2x53 devices only.

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Functional Block Diagram, MSP430G2x13



NOTE: Port P3 is available on 28-pin and 32-pin devices only.



Table 2. Terminal Functions

	TERMINA	L					
		NO.		1/0	DESCRIPTION		
NAME	PW20, N20 PW28 RHB32		RHB32		DESCRIPTION		
P1.0/					General-purpose digital I/O pin		
TA0CLK/					Timer0_A, clock signal TACLK input		
ACLK/	2	2	31	I/O	ACLK signal output		
A0					ADC10 analog input A0 ⁽¹⁾		
CA0					Comparator_A+, CA0 input		
P1.1/					General-purpose digital I/O pin		
TA0.0/					Timer0_A, capture: CCI0A input, compare: Out0 output / BSL transmit		
UCA0RXD/	0	0	_	1/0	USCI_A0 UART mode: receive data input		
UCA0SOMI/	3	3	1	I/O	USCI_A0 SPI mode: slave data out/master in		
A1/					ADC10 analog input A1 ⁽¹⁾		
CA1					Comparator_A+, CA1 input		
P1.2/					General-purpose digital I/O pin		
TA0.1/					Timer0_A, capture: CCl1A input, compare: Out1 output		
UCA0TXD/				1/0	USCI_A0 UART mode: transmit data output		
UCA0SIMO/	4	4	2	I/O	USCI_A0 SPI mode: slave data in/master out		
A2/					ADC10 analog input A2 ⁽¹⁾		
CA2					Comparator_A+, CA2 input		
P1.3/					General-purpose digital I/O pin		
ADC10CLK/				I/O	ADC10, conversion clock output ⁽¹⁾		
A3/	_	_			ADC10 analog input A3 ⁽¹⁾		
VREF-/VEREF-/	5	5	3		ADC10 negative reference voltage (1)		
CA3/					Comparator_A+, CA3 input		
CAOUT					Comparator_A+, output		
P1.4/					General-purpose digital I/O pin		
SMCLK/					SMCLK signal output		
UCB0STE/					USCI_B0 slave transmit enable		
UCA0CLK/	_	_			USCI_A0 clock input/output		
A4/	6	6	4	I/O	ADC10 analog input A4 ⁽¹⁾		
VREF+/VEREF+/					ADC10 positive reference voltage ⁽¹⁾		
CA4/					Comparator_A+, CA4 input		
тск					JTAG test clock, input terminal for device programming and test		
P1.5/					General-purpose digital I/O pin		
TA0.0/					Timer0_A, compare: Out0 output / BSL receive		
UCB0CLK/					USCI_B0 clock input/output		
UCA0STE/			5	I/O	USCI_A0 slave transmit enable		
A5/				ADC10 analog input A5 ⁽¹⁾			
CA5/					Comparator_A+, CA5 input		
TMS					JTAG test mode select, input terminal for device programming and test		



Table 2. Terminal Functions (continued)

TERMINAL									
NAME DW20		1/0	DESCRIPTION						
NAME	PW20, N20	PW28 RHB32		20	DESCRIPTION				
P1.6/					General-purpose digital I/O pin				
TA0.1/					Timer0_A, compare: Out1 output				
A6/					ADC10 analog input A6 ⁽¹⁾				
CA6/	14	22	21	I/O	Comparator_A+, CA6 input				
UCB0SOMI/					USCI_B0 SPI mode: slave out master in				
UCB0SCL/					USCI_B0 I2C mode: SCL I2C clock				
TDI/TCLK					JTAG test data input or test clock input during programming and test				
P1.7/					General-purpose digital I/O pin				
A7/					ADC10 analog input A7 ⁽¹⁾				
CA7/					Comparator_A+, CA7 input				
CAOUT/	15	23	22	I/O	Comparator_A+, output				
UCB0SIMO/	13	20		1/0	USCI_B0 SPI mode: slave in master out				
UCB0SDA/					USCI_B0 I2C mode: SDA I2C data				
TDO/TDI					JTAG test data output terminal or test data input during programming and test ⁽²⁾				
P2.0/		4.0			General-purpose digital I/O pin				
TA1.0	8	10	9	I/O	Timer1_A, capture: CCI0A input, compare: Out0 output				
P2.1/			4.0	- 0	General-purpose digital I/O pin				
TA1.1	9	11	10	I/O	Timer1_A, capture: CCl1A input, compare: Out1 output				
P2.2/	4.0	4.0		- 0	General-purpose digital I/O pin				
TA1.1	10	12	11	I/O	Timer1_A, capture: CCl1B input, compare: Out1 output				
P2.3/	44	40	45	- 0	General-purpose digital I/O pin				
TA1.0	11	16	15	I/O	Timer1_A, capture: CCI0B input, compare: Out0 output				
P2.4/	10	47	10	-	General-purpose digital I/O pin				
TA1.2	12	17	16	I/O	Timer1_A, capture: CCI2A input, compare: Out2 output				
P2.5/	10	40	47	-	General-purpose digital I/O pin				
TA1.2	13	18	17	I/O	Timer1_A, capture: CCI2B input, compare: Out2 output				
XIN/					Input terminal of crystal oscillator				
P2.6/	19	27	26	I/O	General-purpose digital I/O pin				
TA0.1					Timer0_A, compare: Out1 output				
XOUT/	10	00	0.5	-	Output terminal of crystal oscillator ⁽³⁾				
P2.7	18	26	25	I/O	General-purpose digital I/O pin				
P3.0/		0	7	2	General-purpose digital I/O pin				
TA0.2	-	9	7	I/O	Timer0_A, capture: CCl2A input, compare: Out2 output				
P3.1/		0		1/0	General-purpose digital I/O pin				
TA1.0	-	8	6	I/O	Timer1_A, compare: Out0 output				
P3.2/		10	10	1/0	General-purpose digital I/O pin				
TA1.1	-	13	12	I/O	Timer1_A, compare: Out1 output				
P3.3/			40	1,0	General-purpose digital I/O				
TA1.2	-	14	13	I/O	Timer1_A, compare: Out2 output				
P3.4/		4-			General-purpose digital I/O				
TA0.0	-	15	14	I/O	Timer0_A, compare: Out0 output				

⁽²⁾ TDO or TDI is selected via JTAG instruction.

⁽³⁾ If XOUT/P2.7 is used as an input, excess current flows until P2SEL.7 is cleared. This is due to the oscillator output driver connection to this pad after reset.



Table 2. Terminal Functions (continued)

TERMINAL								
		NO.		1/0	DESCRIPTION			
NAME	PW20, N20	PW28	RHB32		DESCRIPTION			
P3.5/		19	18	I/O	General-purpose digital I/O			
TA0.1	-	19	10	1/0	Timer0_A, compare: Out1 output			
P3.6/		20	19	I/O	General-purpose digital I/O			
TA0.2	-	20	19	1/0	Timer0_A, compare: Out2 output			
P3.7/					General-purpose digital I/O			
TA1CLK/	- 21 20		I/O	Timer1_A, clock signal TACLK input				
CAOUT					Comparator_A+, output			
RST/					Reset			
NMI/	16	24	23	- 1	Nonmaskable interrupt input			
SBWTDIO					Spy-Bi-Wire test data input/output during programming and test			
TEST/	17	25	24	ı	Selects test mode for JTAG pins on Port 1. The device protection fuse is connected to TEST.			
SBWTCK					Spy-Bi-Wire test clock input during programming and test			
AVCC	NA	NA	29	NA	Analog supply voltage			
DVCC	1	1	30	NA	A Digital supply voltage			
DVSS	20	28	27, 28	NA	Ground reference			
NC	NA	NA	8, 32	NA	Not connected			
QFN Pad	NA	NA	Pad	NA	QFN package pad. Connection to VSS is recommended.			



SHORT-FORM DESCRIPTION

CPU

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator, respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

The instruction set consists of the original 51 instructions with three formats and seven address modes and additional instructions for the expanded address range. Each instruction can operate on word and byte data.

Instruction Set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. Table 3 shows examples of the three types of instruction formats; Table 4 shows the address modes.

Program Counter	PC/R0
Stack Pointer	SP/R1
Status Register	SR/CG1/R2
Constant Generator	CG2/R3
General-Purpose Register	R4
General-Purpose Register	R5
General-Purpose Register	R6
General-Purpose Register	R7
General-Purpose Register	R8
General-Purpose Register	R9
General-Purpose Register	R10
General-Purpose Register	R11
General-Purpose Register	R12
General-Purpose Register	R13
General-Purpose Register	R14
General-Purpose Register	R15

Table 3. Instruction Word Formats

INSTRUCTION FORMAT	EXAMPLE	OPERATION
Dual operands, source-destination	ADD R4,R5	R4 + R5> R5
Single operands, destination only	CALL R8	PC>(TOS), R8> PC
Relative jump, un/conditional	JNE	Jump-on-equal bit = 0

Table 4. Address Mode Descriptions⁽¹⁾

ADDRESS MODE	S	D	SYNTAX	EXAMPLE	OPERATION
Register	✓	✓	MOV Rs,Rd	MOV R10,R11	R10> R11
Indexed	✓	✓	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5)> M(6+R6)
Symbolic (PC relative)	✓	✓	MOV EDE,TONI		M(EDE)> M(TONI)
Absolute	✓	✓	MOV &MEM,&TCDAT		M(MEM)> M(TCDAT)
Indirect	✓		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10)> M(Tab+R6)
Indirect autoincrement	✓		MOV @Rn+,Rm	MOV @R10+,R11	M(R10)> R11 R10 + 2> R10
Immediate	✓		MOV #X,TONI	MOV #45,TONI	#45> M(TONI)

(1) S = source, D = destination



Operating Modes

The MSP430 has one active mode and five software selectable low-power modes of operation. An interrupt event can wake up the device from any of the low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode (AM)
 - All clocks are active
- Low-power mode 0 (LPM0)
 - CPU is disabled
 - ACLK and SMCLK remain active, MCLK is disabled
- Low-power mode 1 (LPM1)
 - CPU is disabled
 - ACLK and SMCLK remain active, MCLK is disabled
 - DCO's dc generator is disabled if DCO not used in active mode
- Low-power mode 2 (LPM2)
 - CPU is disabled
 - MCLK and SMCLK are disabled
 - DCO's dc generator remains enabled
 - ACLK remains active
- Low-power mode 3 (LPM3)
 - CPU is disabled
 - MCLK and SMCLK are disabled
 - DCO's dc generator is disabled
 - ACLK remains active
- Low-power mode 4 (LPM4)
 - CPU is disabled
 - ACLK is disabled
 - MCLK and SMCLK are disabled
 - DCO's dc generator is disabled
 - Crystal oscillator is stopped



Interrupt Vector Addresses

The interrupt vectors and the power-up starting address are located in the address range 0FFFFh to 0FFC0h. The vector contains the 16-bit address of the appropriate interrupt handler instruction sequence.

If the reset vector (located at address 0FFFEh) contains 0FFFFh (for example, flash is not programmed), the CPU goes into LPM4 immediately after power-up.

Table 5. Interrupt Sources, Flags, and Vectors

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power-Up External Reset Watchdog Timer+ Flash key violation PC out-of-range ⁽¹⁾	PORIFG RSTIFG WDTIFG KEYV ⁽²⁾	Reset	0FFFEh	31, highest int 15
NMI Oscillator fault Flash memory access violation	NMIIFG OFIFG ACCVIFG ⁽²⁾⁽³⁾	(non)-maskable (non)-maskable (non)-maskable	0FFFCh	30 int 14
Timer1_A3	TA1CCR0 CCIFG ⁽⁴⁾	maskable	0FFFAh	29 int 13
Timer1_A3	TA1CCR2 TA1CCR1 CCIFG, TAIFG ⁽²⁾⁽⁴⁾	maskable	0FFF8h	28 int 12
Comparator_A+	CAIFG ⁽⁴⁾	maskable	0FFF6h	27 int 11
Watchdog Timer+	WDTIFG	maskable	0FFF4h	26 int 10
Timer0_A3	TA0CCR0 CCIFG ⁽⁴⁾	maskable	0FFF2h	25 int 09
Timer0_A3	TA0CCR2 TA0CCR1 CCIFG, TAIFG	maskable	0FFF0h	24 int 08
USCI_A0/USCI_B0 receive USCI_B0 I2C status	UCA0RXIFG, UCB0RXIFG ⁽²⁾⁽⁵⁾	maskable	0FFEEh	23 int 07
USCI_A0/USCI_B0 transmit USCI_B0 I2C receive/transmit	UCA0TXIFG, UCB0TXIFG (2) (6)	maskable	0FFECh	22 int 06
ADC10 (MSP430G2x53 only)	ADC10IFG ⁽⁴⁾	maskable	0FFEAh	21 int 05
			0FFE8h	20
I/O Port P2 (up to eight flags)	P2IFG.0 to P2IFG.7 ⁽²⁾⁽⁴⁾	maskable	0FFE6h	19 int 03
I/O Port P1 (up to eight flags)	P1IFG.0 to P1IFG.7 ⁽²⁾⁽⁴⁾	maskable	0FFE4h	18 int 02
			0FFE2h	17
			0FFE0h	16
See (7)			0FFDEh	15
See ⁽⁸⁾			0FFDEh to 0FFC0h	14 to 0, lowest

⁽¹⁾ A reset is generated if the CPU tries to fetch instructions from within the module register memory address range (0h to 01FFh) or from within unused address ranges.

⁽²⁾ Multiple source flags

^{(3) (}non)-maskable: the individual interrupt-enable bit can disable an interrupt event, but the general interrupt enable cannot.

⁽⁴⁾ Interrupt flags are located in the module.

⁽⁵⁾ In SPI mode: UCBORXIFG. In I2C mode: UCALIFG, UCNACKIFG, ICSTTIFG, UCSTPIFG.

⁽⁶⁾ In UART or SPI mode: UCB0TXIFG. In I2C mode: UCB0RXIFG, UCB0TXIFG.

⁽⁷⁾ This location is used as bootstrap loader security key (BSLSKEY). A 0xAA55 at this location disables the BSL completely. A zero (0h) disables the erasure of the flash if an invalid password is supplied.

⁽⁸⁾ The interrupt vectors at addresses 0FFDEh to 0FFC0h are not used in this device and can be used for regular program code if necessary.

OFIE



Special Function Registers (SFRs)

Most interrupt and module enable bits are collected into the lowest address space. Special function register bits not allocated to a functional purpose are not physically present in the device. Simple software access is provided with this arrangement.

Legend rw: Bit can be read and written.

rw-0,1: Bit can be read and written. It is reset or set by PUC. rw-(0,1): Bit can be read and written. It is reset or set by POR.

SFR bit is not present in device.

Table 6. Interrupt Enable Register 1 and 2

Address	7	6	5	4	3	2	1	0
00h			ACCVIE	NMIIE			OFIE	WDTIE
			rw-0	rw-0			rw-0	rw-0
WDTIE	Watchdog		enable. Inactiv	e if watchdog m	ode is selected.	Active if Watch	dog Timer is co	nfigured in

interval timer mode.
Oscillator fault interrupt enable

NMIIE (Non)maskable interrupt enable

ACCVIE Flash access violation interrupt enable

Address	7	6	5	4	3	2	1	0
01h					UCB0TXIE	UCB0RXIE	UCA0TXIE	UCA0RXIE
					rw-0	rw-0	rw-0	rw-0

UCA0RXIE USCI_A0 receive interrupt enable
UCA0TXIE USCI_A0 transmit interrupt enable
UCB0RXIE USCI_B0 receive interrupt enable
UCB0TXIE USCI_B0 transmit interrupt enable

Table 7. Interrupt Flag Register 1 and 2

Address	7	6	5	4	3	2	1	0
02h				NMIIFG	RSTIFG	PORIFG	OFIFG	WDTIFG
				rw-0	rw-(0)	rw-(1)	rw-1	rw-(0)

WDTIFG Set on watchdog timer overflow (in watchdog mode) or security key violation.

Reset on V_{CC} power-on or a reset condition at the RST/NMI pin in reset mode.

OFIFG Flag set on oscillator fault.

PORIFG Power-On Reset interrupt flag. Set on V_{CC} power-up.

RSTIFG External reset interrupt flag. Set on a reset condition at \overline{RST}/NMI pin in reset mode. Reset on V_{CC} power-up.

NMIIFG Set via RST/NMI pin

Address	7	6	5	4	3	2	1	0
03h					UCB0TXIFG	UCB0RXIFG	UCA0TXIFG	UCA0RXIFG
					rw-1	rw-∩	rw-1	rw-O

UCA0RXIFG
UCA0TXIFG
USCI_A0 receive interrupt flag
USCI_A0 transmit interrupt flag
USCI_B0 receive interrupt flag
USCI_B0 transmit interrupt flag
USCI_B0 transmit interrupt flag



Memory Organization

Table 8. Memory Organization

		MSP430G2153	MSP430G2253 MSP430G2213	MSP430G2353 MSP430G2313	MSP430G2453 MSP430G2413	MSP430G2553 MSP430G2513
Memory	Size	1kB	2kB	4kB	8kB	16kB
Main: interrupt vector	Flash	0xFFFF to 0xFFC0	0xFFFF to 0xFFC0	0xFFFF to 0xFFC0	0xFFFF to 0xFFC0	0xFFFF to 0xFFC0
Main: code memory	Flash	0xFFFF to 0xFC00	0xFFFF to 0xF800	0xFFFF to 0xF000	0xFFFF to 0xE000	0xFFFF to 0xC000
Information memory	Size	256 Byte	256 Byte	256 Byte	256 Byte	256 Byte
	Flash	010FFh to 01000h	010FFh to 01000h	010FFh to 01000h	010FFh to 01000h	010FFh to 01000h
RAM	Size	256 Byte	256 Byte	256 Byte	512 Byte	512 Byte
		0x02FF to 0x0200	0x02FF to 0x0200	0x02FF to 0x0200	0x03FF to 0x0200	0x03FF to 0x0200
Peripherals	16-bit	01FFh to 0100h	01FFh to 0100h	01FFh to 0100h	01FFh to 0100h	01FFh to 0100h
	8-bit	0FFh to 010h	0FFh to 010h	0FFh to 010h	0FFh to 010h	0FFh to 010h
	8-bit SFR	0Fh to 00h	0Fh to 00h	0Fh to 00h	0Fh to 00h	0Fh to 00h

Bootstrap Loader (BSL)

The MSP430 BSL enables users to program the flash memory or RAM using a UART serial interface. Access to the MSP430 memory via the BSL is protected by user-defined password. For complete description of the features of the BSL and its implementation, see the MSP430 Programming Via the Bootstrap Loader User's Guide (SLAU319).

Table 9. BSL Function Pins

BSL FUNCTION	BSL FUNCTION 20-PIN PW PACKAGE 20-PIN N PACKAGE		32-PIN PACKAGE RHB	
Data transmit	3 - P1.1	3 - P1.1	1 - P1.1	
Data receive	7 - P1.5	7 - P1.5	5 - P1.5	

Flash Memory

The flash memory can be programmed via the Spy-Bi-Wire/JTAG port or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and four segments of information memory (A to D) of 64 bytes each. Each segment in main memory is 512 bytes in size.
- · Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A to D can be erased individually or as a group with segments 0 to n. Segments A to D are also called *information memory*.
- Segment A contains calibration data. After reset segment A is protected against programming and erasing. It
 can be unlocked but care should be taken not to erase this segment if the device-specific calibration data is
 required.



Peripherals

Peripherals are connected to the CPU through data, address, and control buses and can be handled using all instructions. For complete module descriptions, see the MSP430x2xx Family User's Guide (SLAU144).

Oscillator and System Clock

The clock system is supported by the basic clock module that includes support for a 32768-Hz watch crystal oscillator, an internal very-low-power low-frequency oscillator and an internal digitally controlled oscillator (DCO). The basic clock module is designed to meet the requirements of both low system cost and low power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 1 μ s. The basic clock module provides the following clock signals:

- · Auxiliary clock (ACLK), sourced either from a 32768-Hz watch crystal or the internal LF oscillator.
- · Main clock (MCLK), the system clock used by the CPU.
- Sub-Main clock (SMCLK), the sub-system clock used by the peripheral modules.

The DCO settings to calibrate the DCO output frequency are stored in the information memory segment A.

Main DCO Characteristics

- All ranges selected by RSELx overlap with RSELx + 1: RSELx = 0 overlaps RSELx = 1, ... RSELx = 14 overlaps RSELx = 15.
- DCO control bits DCOx have a step size as defined by parameter S_{DCO}.
- Modulation control bits MODx select how often f_{DCO(RSEL,DCO+1)} is used within the period of 32 DCOCLK cycles. The frequency f_{DCO(RSEL,DCO)} is used for the remaining cycles. The frequency is an average equal to:

$$f_{average} = \frac{32 \times f_{DCO(RSEL,DCO)} \times f_{DCO(RSEL,DCO+1)}}{MOD \times f_{DCO(RSEL,DCO)} + (32 - MOD) \times f_{DCO(RSEL,DCO+1)}}$$



Calibration Data Stored in Information Memory Segment A

Calibration data is stored for both the DCO and for ADC10 organized in a tag-length-value structure.

Table 10. Tags Used by the ADC Calibration Tags

NAME	ADDRESS	VALUE	DESCRIPTION
TAG_DCO_30	0x10F6	0x01	DCO frequency calibration at $V_{CC} = 3 \text{ V}$ and $T_A = 30^{\circ}\text{C}$ at calibration
TAG_ADC10_1	0x10DA	0x10	ADC10_1 calibration tag
TAG_EMPTY	-	0xFE	Identifier for empty memory areas

Table 11. Labels Used by the ADC Calibration Tags

LABEL	ADDRESS OFFSET	SIZE	CONDITION AT CALIBRATION AND DESCRIPTION
CAL_ADC_25T85	0x0010	word	INCHx = 0x1010, REF2_5 = 1, T _A = 85°C
CAL_ADC_25T30	0x000E	word	INCHx = 0x1010, REF2_5 = 1, T _A = 30°C
CAL_ADC_25VREF_FACTOR	0x000C	word	REF2_5 = 1, T _A = 30°C, I _{VREF+} = 1 mA
CAL_ADC_15T85	0x000A	word	INCHx = 0x1010, REF2_5 = 0, T _A = 85°C
CAL_ADC_15T30	0x0008	word	INCHx = 0x1010, REF2_5 = 0, T _A = 30°C
CAL_ADC_15VREF_FACTOR	0x0006	word	REF2_5 = 0, $T_A = 30^{\circ}C$, $I_{VREF+} = 0.5 \text{ mA}$
CAL_ADC_OFFSET	0x0004	word	External VREF = 1.5 V, f _{ADC10CLK} = 5 MHz
CAL_ADC_GAIN_FACTOR	0x0002	word	External VREF = 1.5 V, f _{ADC10CLK} = 5 MHz
CAL_BC1_1MHZ	0x0009	byte	-
CAL_DCO_1MHZ	0x0008	byte	-
CAL_BC1_8MHZ	0x0007	byte	-
CAL_DCO_8MHZ	0x0006	byte	-
CAL_BC1_12MHZ	0x0005	byte	-
CAL_DCO_12MHZ	0x0004	byte	-
CAL_BC1_16MHZ	0x0003	byte	-
CAL_DCO_16MHZ	0x0002	byte	-

Brownout

The brownout circuit is implemented to provide the proper internal reset signal to the device during power on and power off.

Digital I/O

Up to three 8-bit I/O ports are implemented:

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt condition (port P1 and port P2 only) is possible.
- Edge-selectable interrupt input capability for all bits of port P1 and port P2 (if available).
- Read/write access to port-control registers is supported by all instructions.
- Each I/O has an individually programmable pullup or pulldown resistor.
- Each I/O has an individually programmable pin oscillator enable bit to enable low-cost capacitive touch detection.

Watchdog Timer (WDT+)

The primary function of the watchdog timer (WDT+) module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be disabled or configured as an interval timer and can generate interrupts at selected time intervals.



Timer_A3 (TA0, TA1)

Timer0/1_A3 is a 16-bit timer/counter with three capture/compare registers. Timer_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

Table 12. Timer0_A3 Signal Connections

INPUT PIN NUMBER		DEVICE MODULE		MODULE	MODULE	OUTPUT PIN NUMBER			
PW20, N20	PW28	RHB32	INPUT SIGNAL	INPUT NAME	BLOCK	OUTPUT SIGNAL	PW20, N20	PW28	RHB32
P1.0-2	P1.0-2	P1.0-31	TACLK	TACLK					
			ACLK	ACLK	T:	NIA			
			SMCLK	SMCLK	Timer	NA			
PinOsc	PinOsc	PinOsc	TACLK	INCLK					
P1.1-3	P1.1-3	P1.1-1	TA0.0	CCI0A			P1.1-3	P1.1-3	P1.1-1
			ACLK	CCI0B	CCR0 TA0	TA0	P1.5-7	P1.5-7	P1.5-5
			V _{SS}	GND		TAU		P3.4-15	P3.4-14
			V _{CC}	V _{CC}					
P1.2-4	P1.2-4	P1.2-2	TA0.1	CCI1A		TA.	P1.2-4	P1.2-4	P1.2-2
			CAOUT	CCI1B	0004		P1.6-14	P1.6-22	P1.6-21
			V _{SS}	GND	CCR1	TA1	P2.6-19	P2.6-27	P2.6-26
			V _{CC}	V _{CC}				P3.5-19	P3.5-18
	P3.0-9	P3.0-7	TA0.2	CCI2A				P3.0-9	P3.0-7
PinOsc	PinOsc	PinOsc	TA0.2	CCI2B	CCR2	TAO		P3.6-20	P3.6-19
			V _{SS}	GND		TA2			
			V _{CC}	V _{CC}					

Table 13. Timer1_A3 Signal Connections

INPUT PIN NUMBER		DEVICE MODULE		MODULE	MODULE MODULE	OUTPUT PIN NUMBER			
PW20, N20	PW28	RHB32	INPUT SIGNAL	INPUT NAME	BLOCK	OUTPUT SIGNAL	PW20, N20	PW28	RHB32
-	P3.7-21	P3.7-20	TACLK	TACLK					
			ACLK	ACLK	Timer	NA			
			SMCLK	SMCLK	rimer	INA			
-	P3.7-21	P3.7-20	TACLK	INCLK					
P2.0-8	P2.0-10	P2.0-9	TA1.0	CCI0A		TA0	P2.0-8	P2.0-10	P2.0-9
P2.3-11	P2.3-16	P2.3-12	TA1.0	CCI0B	0000		P2.3-11	P2.3-16	P2.3-15
			V _{SS}	GND	CCR0			P3.1-8	P3.1-6
			V _{CC}	V _{CC}					
P2.1-9	P2.1-11	P2.1-10	TA1.1	CCI1A			P2.1-9	P2.1-11	P2.1-10
P2.2-10	P2.2-12	P2.2-11	TA1.1	CCI1B	0004		P2.2-10	P2.2-12	P2.2-11
			V _{SS}	GND	CCR1	TA1		P3.2-13	P3.2-12
			V _{CC}	V _{CC}					
P2.4-12	P2.4-17	P2.4-16	TA1.2	CCI2A			P2.4-12	P2.4-17	P2.4-16
P2.5-13	P2.5-18	P2.5-17	TA1.2	CCI2B	CCDO	TAO	P2.5-13	P2.5-18	P2.5-17
			V _{SS}	GND	CCR2	TA2		P3.3-14	P3.3-13
			V _{CC}	V _{CC}					

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Universal Serial Communications Interface (USCI)

The USCI module is used for serial data communication. The USCI module supports synchronous communication protocols such as SPI (3 or 4 pin) and I2C, and asynchronous communication protocols such as UART, enhanced UART with automatic baudrate detection (LIN), and IrDA. Not all packages support the USCI functionality.

USCI_A0 provides support for SPI (3 or 4 pin), UART, enhanced UART, and IrDA.

USCI_B0 provides support for SPI (3 or 4 pin) and I2C.

Comparator_A+

The primary function of the comparator_A+ module is to support precision slope analog-to-digital conversions, battery-voltage supervision, and monitoring of external analog signals.

ADC10 (MSP430G2x53 Only)

The ADC10 module supports fast 10-bit analog-to-digital conversions. The module implements a 10-bit SAR core, sample select control, reference generator, and data transfer controller (DTC) for automatic conversion result handling, allowing ADC samples to be converted and stored without any CPU intervention.



Peripheral File Map

Table 14. Peripherals With Word Access

MODULE	REGISTER DESCRIPTION	REGISTER NAME	OFFSET
ADC10 (MSP430G2x53 devices only)	ADC data transfer start address	ADC10SA	1BCh
	ADC memory	ADC10MEM	1B4h
	ADC control register 1	ADC10CTL1	1B2h
	ADC control register 0	ADC10CTL0	1B0h
Timer1_A3	Capture/compare register	TA1CCR2	0196h
	Capture/compare register	TA1CCR1	0194h
	Capture/compare register	TA1CCR0	0192h
	Timer_A register	TA1R	0190h
	Capture/compare control	TA1CCTL2	0186h
	Capture/compare control	TA1CCTL1	0184h
	Capture/compare control	TA1CCTL0	0182h
	Timer_A control	TA1CTL	0180h
	Timer_A interrupt vector	TA1IV	011Eh
Timer0_A3	Capture/compare register	TA0CCR2	0176h
	Capture/compare register	TA0CCR1	0174h
	Capture/compare register	TA0CCR0	0172h
	Timer_A register	TA0R	0170h
	Capture/compare control	TA0CCTL2	0166h
	Capture/compare control	TA0CCTL1	0164h
	Capture/compare control	TA0CCTL0	0162h
	Timer_A control	TA0CTL	0160h
	Timer_A interrupt vector	TAOIV	012Eh
Flash Memory	Flash control 3	FCTL3	012Ch
	Flash control 2	FCTL2	012Ah
	Flash control 1	FCTL1	0128h
Watchdog Timer+	Watchdog/timer control	WDTCTL	0120h



Table 15. Peripherals With Byte Access

MODULE	REGISTER DESCRIPTION	REGISTER NAME	OFFSET
USCI_B0	USCI_B0 transmit buffer	UCB0TXBUF	06Fh
	USCI_B0 receive buffer	UCB0RXBUF	06Eh
	USCI_B0 status	UCB0STAT	06Dh
	USCI B0 I2C Interrupt enable	UCB0CIE	06Ch
	USCI_B0 bit rate control 1	UCB0BR1	06Bh
	USCI_B0 bit rate control 0	UCB0BR0	06Ah
	USCI_B0 control 1	UCB0CTL1	069h
	USCI_B0 control 0	UCB0CTL0	068h
	USCI_B0 I2C slave address	UCB0SA	011Ah
	USCI_B0 I2C own address	UCB0OA	0118h
JSCI_A0	USCI_A0 transmit buffer	UCA0TXBUF	067h
	USCI_A0 receive buffer	UCA0RXBUF	066h
	USCI_A0 status	UCA0STAT	065h
	USCI_A0 modulation control	UCA0MCTL	064h
	USCI_A0 baud rate control 1	UCA0BR1	063h
	USCI_A0 baud rate control 0	UCA0BR0	062h
	USCI_A0 control 1	UCA0CTL1	061h
	USCI_A0 control 0	UCA0CTL0	060h
	USCI_A0 IrDA receive control	UCA0IRRCTL	05Fh
	USCI_A0 IrDA transmit control	UCA0IRTCTL	05Eh
	USCI_A0 auto baud rate control	UCA0ABCTL	05Dh
ADC10	ADC analog enable 0	ADC10AE0	04Ah
MSP430G2x53 devices only)	ADC analog enable 1	ADC10AE1	04Bh
	ADC data transfer control register 1	ADC10DTC1	049h
	ADC data transfer control register 0	ADC10DTC0	048h
Comparator_A+	Comparator_A+ port disable	CAPD	05Bh
·	Comparator_A+ control 2	CACTL2	05Ah
	Comparator_A+ control 1	CACTL1	059h
Basic Clock System+	Basic clock system control 3	BCSCTL3	053h
·	Basic clock system control 2	BCSCTL2	058h
	Basic clock system control 1	BCSCTL1	057h
	DCO clock frequency control	DCOCTL	056h
Port P3	Port P3 selection 2. pin	P3SEL2	์ บ ั นอท
28-pin PW and 32-pin Hrib caly)	Port P3 resistor enable	raren	010h
	Port P3 selection	P3SEL	01Bh
	Port P3 direction	P3DIR	01Ah
	Port P3 output	PSOUT	019h
	Port P3 input	P3IN	vich
Port P2	Port P2 selection 2	P2SEL2	042h
	Port P2 resistor enable	P2REN	02Fh
	Port P2 selection	P2SEL	02Eh
	Port P2 interrupt enable	P2IE	02Dh
	Port P2 interrupt edge select	P2IES	02Ch
	Port P2 interrupt flag	P2IFG	02Bh
	Port P2 direction	P2DIR	02Ah
	Port P2 output	P2OUT	02An
	I DILLE CUIDUL	1 2001	しとうロ



Table 15. Peripherals With Byte Access (continued)

MODULE	REGISTER DESCRIPTION	REGISTER NAME	OFFSET
Port P1	Port P1 selection 2	P1SEL2	041h
	Port P1 resistor enable	P1REN	027h
	Port P1 selection	P1SEL	026h
	Port P1 interrupt enable	P1IE	025h
	Port P1 interrupt edge select	P1IES	024h
	Port P1 interrupt flag	P1IFG	023h
	Port P1 direction	P1DIR	022h
	Port P1 output	P1OUT	021h
	Port P1 input	P1IN	020h
Special Function	SFR interrupt flag 2	IFG2	003h
	SFR interrupt flag 1	IFG1	002h
	SFR interrupt enable 2	IE2	001h
	SFR interrupt enable 1	IE1	000h

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Absolute Maximum Ratings(1)

Voltage applied at V _{CC} to V _{SS}	-0.3 V to 4.1 V		
Voltage applied to any pin ⁽²⁾	-0.3 V to V _{CC} + 0.3 V		
Diode current at any device pin	±2 mA		
Character terms are true reason. T. (3)	Unprogrammed device	–55°C to 150°C	
Storage temperature range, T _{stg} ⁽³⁾	Programmed device	-55°C to 150°C	

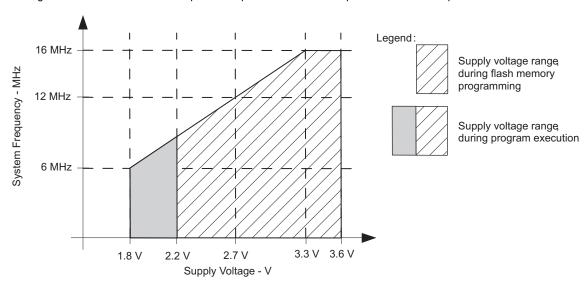
- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages referenced to V_{SS}. The JTAG fuse-blow voltage, V_{FB}, is allowed to exceed the absolute maximum rating. The voltage is applied to the TEST pin when blowing the JTAG fuse.
- (3) Higher temperature may be applied during board soldering according to the current JEDEC J-STD-020 specification with peak reflow temperatures not higher than classified on the device label on the shipping boxes or reels.

Recommended Operating Conditions

Typical values are specified at $V_{CC} = 3.3 \text{ V}$ and $T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

			MIN	NOM	MAX	UNIT
		During program execution	1.8		3.6	
V_{CC}	Supply voltage	During flash programming or erase	2.2		3.6	V
V _{SS}	Supply voltage			0		٧
T _A	Operating free-air temperature	I version	-40		85	°C
	Processor frequency (maximum MCLK frequency) ⁽¹⁾⁽²⁾	V _{CC} = 1.8 V, Duty cycle = 50% ± 10%	dc	6		
f _{SYSTEM}		V _{CC} = 2.7 V, Duty cycle = 50% ± 10%	dc		12	MHz
		V _{CC} = 3.3 V, Duty cycle = 50% ± 10%	dc		16	

- (1) The MSP430 CPU is clocked directly with MCLK. Both the high and low phase of MCLK must not exceed the pulse duration of the specified maximum frequency.
- (2) Modules might have a different maximum input clock specification. See the specification of the respective module in this data sheet.



Note: Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum V_{CC} of 2.2 V.

Figure 1. Safe Operating Area



Electrical Characteristics

Active Mode Supply Current Into V_{CC} Excluding External Current

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (1) (2)

PARAMET	TER	TEST CONDITIONS	T _A	V _{CC}	MIN TYP	MAX	UNIT
		$f_{DCO} = f_{MCLK} = f_{SMCLK} = 1 \text{ MHz},$		2.2 V	230		
	mode (AM) at 1 MHz	f _{ACLK} = 0 Hz, Program executes in flash, BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0		3 V	330	420	μΑ

- (1) All inputs are tied to 0 V or to V_{CC}. Outputs do not source or sink any current.
 (2) The currents are characterized with a Micro Crystal CC4V-T1A SMD crystal with a load capacitance of 9 pF. The internal and external load capacitance is chosen to closely match the required 9 pF.

Typical Characteristics, Active Mode Supply Current (Into V_{cc})



Figure 2. Active Mode Current vs V_{CC} , $T_A = 25$ °C

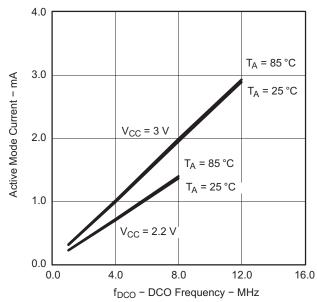


Figure 3. Active Mode Current vs DCO Frequency



Low-Power Mode Supply Currents (Into V_{cc}) Excluding External Current

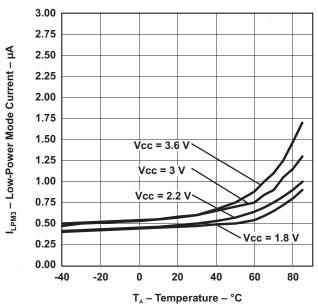
over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (1) (2)

P	ARAMETER	TEST CONDITIONS	T _A	V _{cc}	MIN TYP	MAX	UNIT
I _{LPM0,1MHz}	Low-power mode 0 (LPM0) current (3)	$ \begin{aligned} f_{\text{MCLK}} &= 0 \text{ MHz}, \\ f_{\text{SMCLK}} &= f_{\text{DCO}} = 1 \text{ MHz}, \\ f_{\text{ACLK}} &= 32768 \text{ Hz}, \\ \text{BCSCTL1} &= \text{CALBC1_1MHZ}, \\ \text{DCOCTL} &= \text{CALDCO_1MHZ}, \\ \text{CPUOFF} &= 1, \text{SCG0} = 0, \text{SCG1} = 0, \\ \text{OSCOFF} &= 0 \end{aligned} $	25°C	2.2 V	56		μΑ
I _{LPM2}	Low-power mode 2 (LPM2) current ⁽⁴⁾	$\begin{split} &f_{\text{MCLK}} = f_{\text{SMCLK}} = 0 \text{ MHz}, \\ &f_{\text{DCO}} = 1 \text{ MHz}, \\ &f_{\text{ACLK}} = 32768 \text{ Hz}, \\ &\text{BCSCTL1} = \text{CALBC1_1MHZ}, \\ &\text{DCOCTL} = \text{CALDCO_1MHZ}, \\ &\text{CPUOFF} = 1, \text{SCG0} = 0, \text{SCG1} = 1, \\ &\text{OSCOFF} = 0 \end{split}$	25°C	2.2 V	22		μΑ
I _{LPM3,LFXT1}	Low-power mode 3 (LPM3) current ⁽⁴⁾	$ \begin{aligned} f_{DCO} &= f_{MCLK} = f_{SMCLK} = 0 \text{ MHz}, \\ f_{ACLK} &= 32768 \text{ Hz}, \\ CPUOFF &= 1, SCG0 = 1, SCG1 = 1, \\ OSCOFF &= 0 \end{aligned} $	25°C	2.2 V	0.7	1.5	μΑ
I _{LPM3,VLO}	Low-power mode 3 current, (LPM3) ⁽⁴⁾	$ \begin{aligned} &f_{DCO} = f_{MCLK} = f_{SMCLK} = 0 \text{ MHz}, \\ &f_{ACLK} \text{ from internal LF oscillator (VLO),} \\ &CPUOFF = 1, SCG0 = 1, SCG1 = 1, \\ &OSCOFF = 0 \end{aligned} $	25°C	2.2 V	0.5	0.7	μΑ
		$f_{DCO} = f_{MCLK} = f_{SMCLK} = 0 \text{ MHz},$	25°C		0.1	0.5	
I _{LPM4}	Low-power mode 4 (LPM4) current ⁽⁵⁾	f _{ACLK} = 0 Hz, CPUOFF = 1, SCG0 = 1, SCG1 = 1, OSCOFF = 1	85°C	2.2 V	0.8	1.7	μΑ

- (1) All inputs are tied to 0 V or to V_{CC} . Outputs do not source or sink any current.
- (2) The currents are characterized with a Micro Crystal CC4V-T1A SMD crystal with a load capacitance of 9 pF. The internal and external load capacitance is chosen to closely match the required 9 pF.
- (3) Current for brownout and WDT clocked by SMCLK included.
- (4) Current for brownout and WDT clocked by ACLK included.
- (5) Current for brownout included.

Typical Characteristics, Low-Power Mode Supply Currents

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)





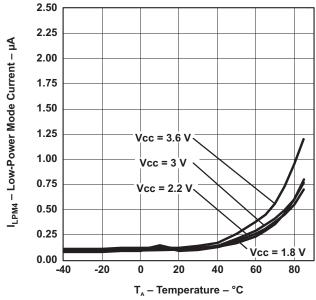


Figure 5. LPM4 Current vs Temperature



Schmitt-Trigger Inputs, Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
V	Positive gaing input threshold voltage			0.45 V _{CC}		0.75 V _{CC}	V
V_{IT+}	Positive-going input threshold voltage		3 V	1.35		2.25	V
V	Negative going input threshold valtage			0.25 V _{CC}		0.55 V _{CC}	V
V _{IT}	Negative-going input threshold voltage		3 V	0.75		1.65	V
V_{hys}	Input voltage hysteresis (V _{IT+} - V _{IT-})		3 V	0.3		1	V
R _{Pull}	Pullup/pulldown resistor	For pullup: V _{IN} = V _{SS} For pulldown: V _{IN} = V _{CC}	3 V	20	35	50	kΩ
C _I	Input capacitance	$V_{IN} = V_{SS}$ or V_{CC}			5		pF

Leakage Current, Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	v_{cc}	MIN MAX	UNIT
I _{lkg(Px.y)} High-impedance leakage curre	(1) (2)	3 V	±50	nA

- The leakage current is measured with V_{SS} or V_{CC} applied to the corresponding pin(s), unless otherwise noted. The leakage of the digital port pins is measured individually. The port pin is selected for input and the pullup/pulldown resistor is disabled.

Outputs, Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
V_{OH}	High-level output voltage	$I_{(OHmax)} = -6 \text{ mA}^{(1)}$	3 V	\	/ _{CC} – 0.3		٧
V_{OL}	Low-level output voltage	$I_{(OLmax)} = 6 \text{ mA}^{(1)}$	3 V	,	V _{SS} + 0.3		٧

⁽¹⁾ The maximum total current, I_(OHmax), and I_(OLmax), for all outputs combined should not exceed ±48 mA to hold the maximum voltage drop

Output Frequency, Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

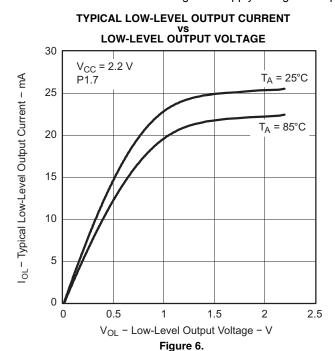
	PARAMETER	TEST CONDITIONS	V _{CC}	MIN TYP	MAX	UNIT
f _{Px.y}	Port output frequency (with load)	Px.y, $C_L = 20 \text{ pF}$, $R_L = 1 \text{ k}\Omega^{(1)}$ (2)	3 V	12		MHz
f _{Port_CLK}	Clock output frequency	$Px.y, C_L = 20 pF^{(2)}$	3 V	16		MHz

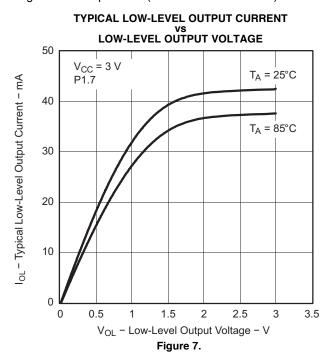
- A resistive divider with two 0.5-kΩ resistors between V_{CC} and V_{SS} is used as load. The output is connected to the center tap of the divider.
- The output voltage reaches at least 10% and 90% V_{CC} at the specified toggle frequency.



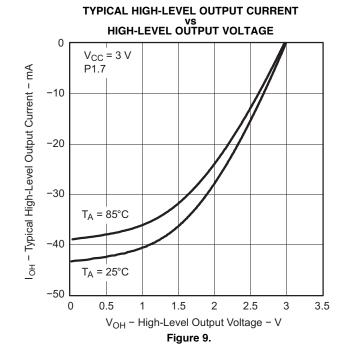
Typical Characteristics, Outputs

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)





TYPICAL HIGH-LEVEL OUTPUT CURRENT VS HIGH-LEVEL OUTPUT VOLTAGE 0 $V_{CC} = 2.2 \text{ V}$ I_{OH} - Typical High-Level Output Current - mA P1.7 -10-15 T_A = 85°C -20 $T_A = 25^{\circ}C$ -25 0 0.5 2 1.5 2.5 V_{OH} - High-Level Output Voltage - V Figure 8.





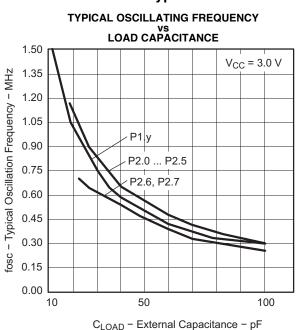
Pin-Oscillator Frequency - Ports Px

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	v_{cc}	MIN TYP	MAX	UNIT
40	Dort output agaillation fraguency	P1.y, $C_L = 10 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$	2.1/	1400		1.11-
fo _{P1.x}	Port output oscillation frequency	P1.y, $C_L = 20 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$	3 V 900			kHz
4-	Don't subsuit assillation for success.	P2.0 to P2.5, $C_L = 10 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$		1800		LI I=
fo _{P2.x}	Port output oscillation frequency	P2.0 to P2.5, $C_L = 20 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$	3 V	1000		kHz
fo _{P2.6/7}	Port output oscillation frequency	P2.6 and P2.7, $C_L = 20 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$	3 V	700		kHz
fo _{P3.x}	Dort output agaillation fraguency	P3.y, $C_L = 10 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$		1800		kHz
	Port output oscillation frequency	P3.y, $C_L = 20 \text{ pF}$, $R_L = 100 \text{ k}\Omega^{(1)(2)}$		1000	1000	

A resistive divider with two 50-kΩ resistors between V_{CC} and V_{SS} is used as load. The output is connected to the center tap of the divider.

Typical Characteristics, Pin-Oscillator Frequency



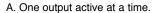
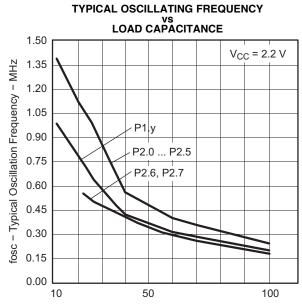


Figure 10.



C_{LOAD} - External Capacitance - pF

A. One output active at a time.

Figure 11.

⁽²⁾ The output voltage reaches at least 10% and 90% V_{CC} at the specified toggle frequency.



POR, BOR⁽¹⁾⁽²⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN TYP	MAX	UNIT
$V_{\text{CC(start)}}$	See Figure 12	dV _{CC} /dt ≤ 3 V/s		0.7 × V _(B_IT)		٧
V _(B_IT-)	See Figure 12 through Figure 14	dV _{CC} /dt ≤ 3 V/s		1.35		٧
V _{hys(B_IT-)}	See Figure 12	dV _{CC} /dt ≤ 3 V/s		140		mV
t _{d(BOR)}	See Figure 12			2000		μs
t _(reset)	Pulse duration needed at RST/NMI pin to accepted reset internally		2.2 V	2		μs

- The current consumption of the brownout module is already included in the I_{CC} current consumption data. The voltage level V_(B_IT-) + V_{hys(B_IT-)}is ≤ 1.8 V.
- (2) During power up, the CPU begins code execution following a period of t_{d(BOR)} after V_{CC} = V_(B_IT-) + V_{hys(B_IT-)}. The default DCO settings must not be changed until V_{CC} ≥ V_{(CC(min)}, where V_{CC(min)} is the minimum supply voltage for the desired operating frequency.

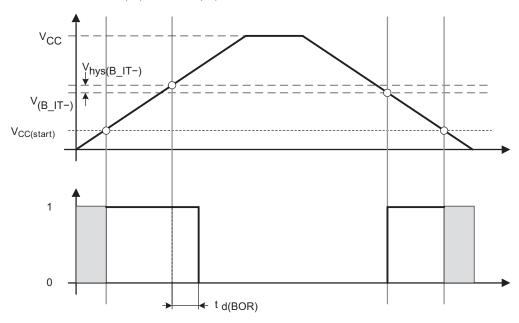


Figure 12. POR and BOR vs Supply Voltage



Typical Characteristics, POR and BOR

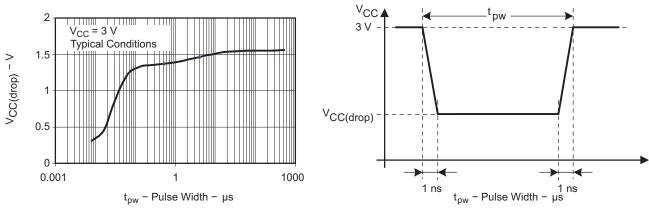


Figure 13. V_{CC(drop)} Level With a Square Voltage Drop to Generate a POR or BOR Signal

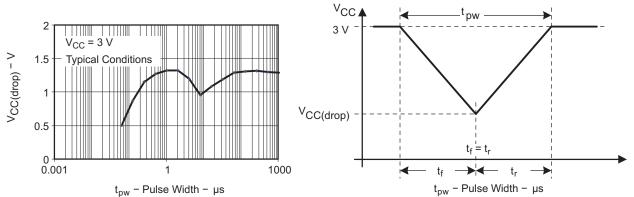


Figure 14. $V_{CC(drop)}$ Level With a Triangle Voltage Drop to Generate a POR or BOR Signal



DCO Frequency

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
		RSELx < 14		1.8		3.6	
V_{CC}	Supply voltage	RSELx = 14		2.2		3.6	V
		RSELx = 15		3		3.6	
f _{DCO(0,0)}	DCO frequency (0, 0)	RSELx = 0, $DCOx = 0$, $MODx = 0$	3 V	0.06		0.14	MHz
f _{DCO(0,3)}	DCO frequency (0, 3)	RSELx = 0, $DCOx = 3$, $MODx = 0$	3 V	0.07		0.17	MHz
f _{DCO(1,3)}	DCO frequency (1, 3)	RSELx = 1, $DCOx = 3$, $MODx = 0$	3 V		0.15		MHz
f _{DCO(2,3)}	DCO frequency (2, 3)	RSELx = 2, $DCOx = 3$, $MODx = 0$	3 V		0.21		MHz
f _{DCO(3,3)}	DCO frequency (3, 3)	RSELx = 3, DCOx = 3, MODx = 0	3 V		0.30		MHz
f _{DCO(4,3)}	DCO frequency (4, 3)	RSELx = 4, $DCOx = 3$, $MODx = 0$	3 V		0.41		MHz
f _{DCO(5,3)}	DCO frequency (5, 3)	RSELx = 5, $DCOx = 3$, $MODx = 0$	3 V		0.58		MHz
f _{DCO(6,3)}	DCO frequency (6, 3)	RSELx = 6, $DCOx = 3$, $MODx = 0$	3 V	0.54		1.06	MHz
f _{DCO(7,3)}	DCO frequency (7, 3)	RSELx = 7, DCOx = 3, MODx = 0	3 V	0.80		1.50	MHz
f _{DCO(8,3)}	DCO frequency (8, 3)	RSELx = 8, DCOx = 3, MODx = 0	3 V		1.6		MHz
f _{DCO(9,3)}	DCO frequency (9, 3)	RSELx = 9, DCOx = 3, MODx = 0	3 V		2.3		MHz
f _{DCO(10,3)}	DCO frequency (10, 3)	RSELx = 10, $DCOx = 3$, $MODx = 0$	3 V		3.4		MHz
f _{DCO(11,3)}	DCO frequency (11, 3)	RSELx = 11, DCOx = 3, MODx = 0	3 V		4.25		MHz
f _{DCO(12,3)}	DCO frequency (12, 3)	RSELx = 12, $DCOx = 3$, $MODx = 0$	3 V	4.30		7.30	MHz
f _{DCO(13,3)}	DCO frequency (13, 3)	RSELx = 13, DCOx = 3, MODx = 0	3 V	6.00	7.8	9.60	MHz
f _{DCO(14,3)}	DCO frequency (14, 3)	RSELx = 14, DCOx = 3, MODx = 0	3 V	8.60		13.9	MHz
f _{DCO(15,3)}	DCO frequency (15, 3)	RSELx = 15, $DCOx = 3$, $MODx = 0$	3 V	12.0		18.5	MHz
f _{DCO(15,7)}	DCO frequency (15, 7)	RSELx = 15, $DCOx = 7$, $MODx = 0$	3 V	16.0		26.0	MHz
S _{RSEL}	Frequency step between range RSEL and RSEL+1	$S_{RSEL} = f_{DCO(RSEL+1,DCO)}/f_{DCO(RSEL,DCO)}$	3 V		1.35		ratio
S _{DCO}	Frequency step between tap DCO and DCO+1	$S_{DCO} = f_{DCO(RSEL,DCO+1)}/f_{DCO(RSEL,DCO)}$	3 V		1.08		ratio
	Duty cycle	Measured at SMCLK output	3 V		50		%



Calibrated DCO Frequencies, Tolerance

PARAMETER	TEST CONDITIONS	T _A	V _{cc}	MIN	TYP	MAX	UNIT
1-MHz tolerance over temperature ⁽¹⁾	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, calibrated at 30°C and 3 V	0°C to 85°C	3 V	-3	±0.5	+3	%
1-MHz tolerance over V _{CC}	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, calibrated at 30°C and 3 V	30°C	1.8 V to 3.6 V	-3	±2	+3	%
1-MHz tolerance overall	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, calibrated at 30°C and 3 V	-40°C to 85°C	1.8 V to 3.6 V	-6	±3	+6	%
8-MHz tolerance over temperature ⁽¹⁾	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, calibrated at 30°C and 3 V	0°C to 85°C	3 V	-3	±0.5	+3	%
8-MHz tolerance over V _{CC}	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, calibrated at 30°C and 3 V	30°C	2.2 V to 3.6 V	-3	±2	+3	%
8-MHz tolerance overall	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, calibrated at 30°C and 3 V	-40°C to 85°C	2.2 V to 3.6 V	-6	±3	+6	%
12-MHz tolerance over temperature ⁽¹⁾	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, calibrated at 30°C and 3 V	0°C to 85°C	3 V	-3	±0.5	+3	%
12-MHz tolerance over V _{CC}	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, calibrated at 30°C and 3 V	30°C	2.7 V to 3.6 V	-3	±2	+3	%
12-MHz tolerance overall	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, calibrated at 30°C and 3 V	-40°C to 85°C	2.7 V to 3.6 V	-6	±3	+6	%
16-MHz tolerance over temperature ⁽¹⁾	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ, calibrated at 30°C and 3 V	0°C to 85°C	3 V	-3	±0.5	+3	%
16-MHz tolerance over V _{CC}	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ, calibrated at 30°C and 3 V	30°C	3.3 V to 3.6 V	-3	±2	+3	%
16-MHz tolerance overall	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ, calibrated at 30°C and 3 V	-40°C to 85°C	3.3 V to 3.6 V	-6	±3	+6	%

⁽¹⁾ This is the frequency change from the measured frequency at 30°C over temperature.



Wake-Up From Lower-Power Modes (LPM3/4)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{cc}	MIN	I TYP MAX		UNIT
t _{DCO,LPM3/4}	DCO clock wake-up time from LPM3/4 ⁽¹⁾	BCSCTL1 = CALBC1_1MHz, DCOCTL = CALDCO_1MHz	3 V		1.5		μs
t _{CPU,LPM3/4}	CPU wake-up time from LPM3/4 (2)			1/f _{MCLK} + t _{Clock,LPM3/4}			

The DCO clock wake-up time is measured from the edge of an external wake-up signal (e.g., port interrupt) to the first clock edge observable externally on a clock pin (MCLK or SMCLK).

Parameter applicable only if DCOCLK is used for MCLK.

Typical Characteristics, DCO Clock Wake-Up Time From LPM3/4

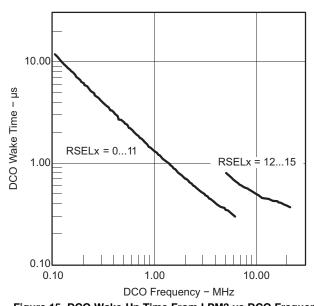


Figure 15. DCO Wake-Up Time From LPM3 vs DCO Frequency



Crystal Oscillator, XT1, Low-Frequency Mode⁽¹⁾

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
f _{LFXT1,LF}	LFXT1 oscillator crystal frequency, LF mode 0, 1	XTS = 0, LFXT1Sx = 0 or 1	1.8 V to 3.6 V		32768		Hz
f _{LFXT1,LF,logic}	LFXT1 oscillator logic level square wave input frequency, LF mode	XTS = 0, XCAPx = 0, LFXT1Sx = 3	1.8 V to 3.6 V	10000	32768	50000	Hz
04	Oscillation allowance for	$XTS = 0$, $LFXT1Sx = 0$, $f_{LFXT1,LF} = 32768$ Hz, $C_{L,eff} = 6$ pF			500		1.0
OA _{LF}	LF crystals	$XTS = 0$, $LFXT1Sx = 0$, $f_{LFXT1,LF} = 32768$ Hz, $C_{L,eff} = 12$ pF			200		kΩ
		XTS = 0, $XCAPx = 0$			1		
0	Integrated effective load	XTS = 0, XCAPx = 1			5.5		,r
$C_{L,eff}$	capacitance, LF mode (2)	XTS = 0, XCAPx = 2			8.5		pF
		XTS = 0, XCAPx = 3			11		
	Duty cycle, LF mode	XTS = 0, Measured at P2.0/ACLK, f _{LFXT1,LF} = 32768 Hz	2.2 V	30	50	70	%
f _{Fault,LF}	Oscillator fault frequency, LF mode ⁽³⁾	XTS = 0, XCAPx = 0, LFXT1Sx = 3 ⁽⁴⁾	2.2 V	10		10000	Hz

- (1) To improve EMI on the XT1 oscillator, the following guidelines should be observed.
 - (a) Keep the trace between the device and the crystal as short as possible.
 - (b) Design a good ground plane around the oscillator pins.
 - (c) Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - (d) Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.

 - (e) Use assembly materials and process that avoid any parasitic load on the oscillator XIN and XOUT pins.

 (f) If a conformal coating is used, ensure that it does not induce capacitive or resistive leakage between the oscillator pins.
 - (g) Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.
- (2) Includes parasitic bond and package capacitance (approximately 2 pF per pin).
 - Because the PCB adds additional capacitance, it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup, the effective load capacitance should always match the specification of the used crystal.
- Frequencies below the MIN specification set the fault flag. Frequencies above the MAX specification do not set the fault flag. Frequencies in between might set the flag.
- Measured with logic-level input frequency but also applies to operation with crystals.

Internal Very-Low-Power Low-Frequency Oscillator (VLO)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	T _A	V _{cc}	MIN	TYP	MAX	UNIT
f_{VLO}	VLO frequency	-40°C to 85°C	3 V	4	12	20	kHz
df_{VLO}/d_{T}	VLO frequency temperature drift	-40°C to 85°C	3 V		0.5		%/°C
df_{VLO}/dV_{CC}	VLO frequency supply voltage drift	25°C	1.8 V to 3.6 V	·	4		%/V

Timer A

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f_{TA}	Timer_A input clock frequency	SMCLK, duty cycle = 50% ± 10%			f _{SYSTEM}		MHz
t _{TA,cap}	Timer_A capture timing	TA0, TA1	3 V	20			ns



USCI (UART Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
f _{USCI}	USCI input clock frequency	SMCLK, duty cycle = 50% ± 10%			f _{SYSTEM}		MHz
f _{max,BITCLK}	Maximum BITCLK clock frequency (equals baudrate in MBaud) ⁽¹⁾		3 V	2			MHz
t _T	UART receive deglitch time ⁽²⁾		3 V	50	100	600	ns

⁽¹⁾ The DCO wake-up time must be considered in LPM3 and LPM4 for baud rates above 1 MHz.

USCI (SPI Master Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 16 and Figure 17)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{USCI}	USCI input clock frequency	SMCLK, duty cycle = 50% ± 10%				f _{SYSTEM}	MHz
t _{SU,MI}	SOMI input data setup time		3 V	75			ns
t _{HD,MI}	SOMI input data hold time		3 V	0			ns
t _{VALID,MO}	SIMO output data valid time	UCLK edge to SIMO valid, C _L = 20 pF	3 V			20	ns

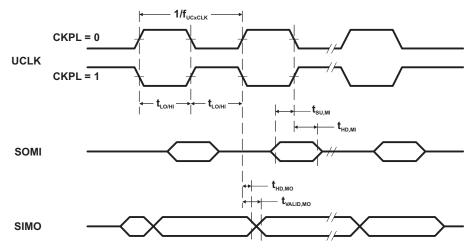


Figure 16. SPI Master Mode, CKPH = 0

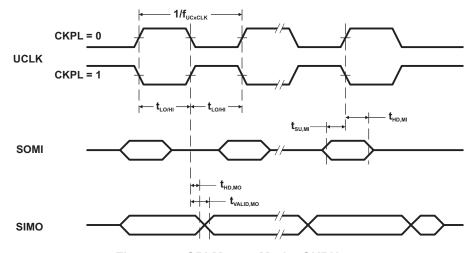


Figure 17. SPI Master Mode, CKPH = 1

²⁾ Pulses on the UART receive input (UCxRX) shorter than the UART receive deglitch time are suppressed. To ensure that pulses are correctly recognized, their duration should exceed the maximum specification of the deglitch time.



USCI (SPI Slave Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 18 and Figure 19)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
t _{STE,LEAD}	STE lead time, STE low to clock		3 V		50		ns
t _{STE,LAG}	STE lag time, Last clock to STE high		3 V	10			ns
t _{STE,ACC}	STE access time, STE low to SOMI data out		3 V		50		ns
t _{STE,DIS}	STE disable time, STE high to SOMI high impedance		3 V		50		ns
t _{SU,SI}	SIMO input data setup time		3 V	15			ns
t _{HD,SI}	SIMO input data hold time		3 V	10			ns
t _{VALID,SO}	SOMI output data valid time	UCLK edge to SOMI valid, C _L = 20 pF	3 V		50	75	ns

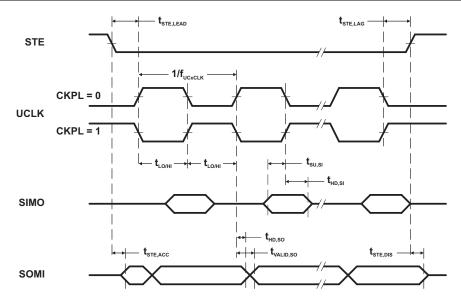


Figure 18. SPI Slave Mode, CKPH = 0

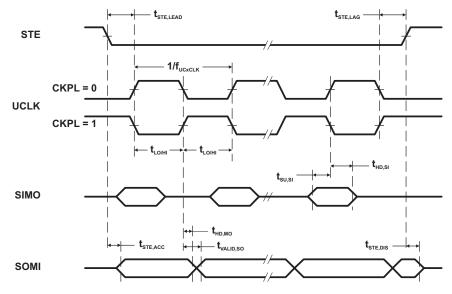


Figure 19. SPI Slave Mode, CKPH = 1



USCI (I2C Mode)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 20)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
f _{USCI}	USCI input clock frequency	SMCLK, duty cycle = 50% ± 10%				f _{SYSTEM}	MHz
f _{SCL}	SCL clock frequency		3 V	0		400	kHz
	Hold times (repeated) CTART	f _{SCL} ≤ 100 kHz	0.1/	4.0			
t _{HD,STA}	Hold time (repeated) START	f _{SCL} > 100 kHz	3 V	0.6			μs
	Catura time a few a way and add CTART	f _{SCL} ≤ 100 kHz	0.1/	4.7			μs
t _{SU,STA}	Setup time for a repeated START	f _{SCL} > 100 kHz	3 V	0.6			
t _{HD,DAT}	Data hold time		3 V	0			ns
t _{SU,DAT}	Data setup time		3 V	250			ns
t _{SU,STO}	Setup time for STOP		3 V	4.0			μs
t _{SP}	Pulse width of spikes suppressed by input filter		3 V	50	100	600	ns

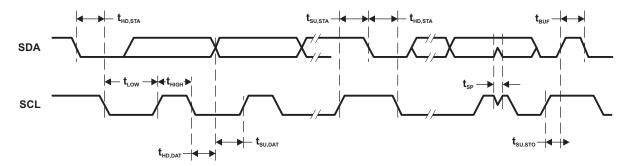


Figure 20. I2C Mode Timing

Comparator_A+

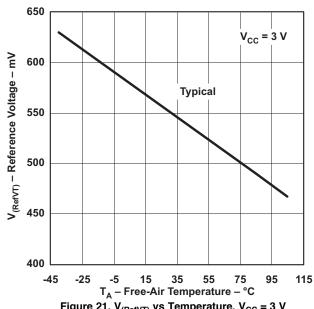
	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
I _(DD) (1)		CAON = 1, CARSEL = 0, CAREF = 0	3 V		45		μΑ
I _{(Refladder/} RefDiode)		CAON = 1, CARSEL = 0, CAREF = 1, 2, or 3, No load at CA0 and CA1	3 V		45		μΑ
V _(IC)	Common-mode input voltage	CAON = 1	3 V	0		V _{CC} -1	V
V _(Ref025)	(Voltage at 0.25 V _{CC} node) / V _{CC}	PCA0 = 1, CARSEL = 1, CAREF = 1, No load at CA0 and CA1	3 V		0.24		
V _(Ref050)	(Voltage at 0.5 V _{CC} node) / V _{CC}	PCA0 = 1, CARSEL = 1, CAREF = 2, No load at CA0 and CA1	3 V		0.48		
V _(RefVT)	See Figure 21 and Figure 22	PCA0 = 1, CARSEL = 1, CAREF = 3, No load at CA0 and CA1, TA = 85°C	3 V		490		mV
V _(offset)	Offset voltage ⁽²⁾		3 V		±10		mV
V _{hys}	Input hysteresis	CAON = 1	3 V		0.7		mV
	Response time	T _A = 25°C, Overdrive 10 mV, Without filter: CAF = 0	2.1/		120		ns
t(response)	(low-high and high-low)	T _A = 25°C, Overdrive 10 mV, With filter: CAF = 1	3 V		1.5		μs

The leakage current for the Comparator_A+ terminals is identical to I_{lkg(Px,y)} specification.

The input offset voltage can be cancelled by using the CAEX bit to invert the Comparator_A+ inputs on successive measurements. The two successive measurements are then summed together.



Typical Characteristics - Comparator_A+



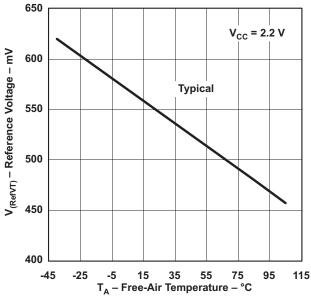
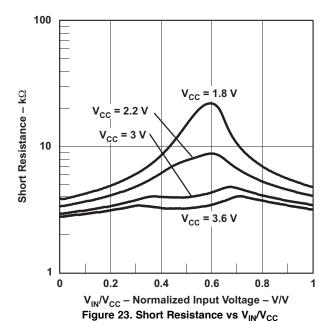


Figure 21. $V_{(RefVT)}$ vs Temperature, $V_{CC} = 3 V$







10-Bit ADC, Power Supply and Input Range Conditions (MSP430G2x53 Only)

	PARAMETER	TEST CONDITIONS	T _A	V _{CC}	MIN	TYP	MAX	UNIT
V _{CC}	Analog supply voltage	V _{SS} = 0 V			2.2		3.6	٧
V _{Ax}	Analog input voltage (2)	All Ax terminals, Analog inputs selected in ADC10AE register		3 V	0		V_{CC}	٧
I _{ADC10}	ADC10 supply current ⁽³⁾	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 1, REFON = 0, ADC10SHT0 = 1, ADC10SHT1 = 0, ADC10DIV = 0	25°C	3 V		0.6		mA
	Reference supply current,	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 0, REF2_5V = 0, REFON = 1, REFOUT = 0	0500	0.1/		0.25		A
I _{REF+}	Reference supply current, reference buffer disabled (4)	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 0, REF2_5V = 1, REFON = 1, REFOUT = 0	25°C	3 V		0.25		mA
I _{REFB,0}	Reference buffer supply current with ADC10SR = 0 ⁽⁴⁾	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 0, REFON = 1, REF2_5V = 0, REFOUT = 1, ADC10SR = 0	25°C	3 V		1.1		mA
I _{REFB,1}	Reference buffer supply current with ADC10SR = 1 (4)	f _{ADC10CLK} = 5.0 MHz, ADC10ON = 0, REFON = 1, REF2_5V = 0, REFOUT = 1, ADC10SR = 1	25°C	3 V		0.5		mA
C _I	Input capacitance	Only one terminal Ax can be selected at one time	25°C	3 V			27	pF
R _I	Input MUX ON resistance	$0 \text{ V} \leq \text{V}_{Ax} \leq \text{V}_{CC}$	25°C	3 V		1000		Ω

The leakage current is defined in the leakage current table with Px.y/Ax parameter.

The analog input voltage range must be within the selected reference voltage range V_{B+} to V_{B-} for valid conversion results.

The internal reference supply current is not included in current consumption parameter $I_{ADC_{10}}$. The internal reference current is supplied via terminal V_{CC} . Consumption is independent of the ADC10ON control bit, unless a conversion is active. The REFON bit enables the built-in reference to settle before starting an A/D conversion.



10-Bit ADC, Built-In Voltage Reference (MSP430G2x53 Only)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
V	Positive built-in reference	I _{VREF+} ≤ 1 mA, REF2_5V = 0		2.2			V
$V_{CC,REF+}$	analog supply voltage range	I _{VREF+} ≤ 1 mA, REF2_5V = 1		2.9			V
V	Positive built-in reference	$I_{VREF+} \le I_{VREF+} max$, REF2_5V = 0	3 V	1.41	1.5	1.59	V
V_{REF+}	voltage	$I_{VREF+} \le I_{VREF+}$ max, REF2_5V = 1	3 V	2.35	2.5	2.65	v
I _{LD,VREF+}	Maximum VREF+ load current		3 V			±1	mA
	VDEE , load regulation	I_{VREF+} = 500 μ A ± 100 μ A, Analog input voltage $V_{Ax} \neq 0.75$ V, REF2_5V = 0	2.1/			±2	LSB
	VREF+ load regulation	EF+ load regulation $I_{VREF+} = 500 \ \mu A \pm 100 \ \mu A,$ Analog input voltage $V_{Ax} \neq 1.25 \ V$, REF2_5V = 1					LSB
	V _{REF+} load regulation response time	$I_{VREF+} = 100 \ \mu A \rightarrow 900 \ \mu A,$ $V_{Ax} \neq 0.5 \times VREF+,$ Error of conversion result ≤ 1 LSB, ADC10SR = 0	3 V			400	ns
C _{VREF+}	Maximum capacitance at pin VREF+	I _{VREF+} ≤ ±1 mA, REFON = 1, REFOUT = 1	3 V			100	pF
TC _{REF+}	Temperature coefficient ⁽¹⁾	I _{VREF+} = const with 0 mA ≤ I _{VREF+} ≤ 1 mA	3 V			±100	ppm/ °C
t _{REFON}	Settling time of internal reference voltage to 99.9% VREF	$I_{VREF+} = 0.5 \text{ mA}, REF2_5V = 0,$ REFON = 0 \rightarrow 1	3.6 V			30	μs
t _{REFBURST}	Settling time of reference buffer to 99.9% VREF	I _{VREF+} = 0.5 mA, REF2_5V = 1, REFON = 1, REFBURST = 1, ADC10SR = 0	3 V			2	μs

⁽¹⁾ Calculated using the box method: (MAX(-40 to 85°C) – MIN(-40 to 85°C)) / MIN(-40 to 85°C) / (85°C – (-40°C))



10-Bit ADC, External Reference⁽¹⁾ (MSP430G2x53 Only)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT	
VEREF+	Positive external reference input	VEREF+ > VEREF-, SREF1 = 1, SREF0 = 0		1.4		V _{CC}	V	
VEILEI T	voltage range (2)	VEREF- \leq VEREF+ \leq V _{CC} $-$ 0.15 V, SREF1 = 1, SREF0 = 1 (3)		1.4		3	V	
VEREF-	Negative external reference input voltage range ⁽⁴⁾	VEREF+ > VEREF-		0		1.2	V	
ΔVEREF	Differential external reference input voltage range, ΔVEREF = VEREF+ - VEREF-	VEREF+ > VEREF- (5)		1.4		V_{CC}	V	
	Static input current into VEREF+	$0 \text{ V} \leq \text{VEREF+} \leq \text{V}_{CC},$ SREF1 = 1, SREF0 = 0	3 V		±1		Δ	
IVEREF+	Static input current into VEREF+	$0 \text{ V} \le \text{VEREF+} \le \text{V}_{\text{CC}} - 0.15 \text{ V} \le 3 \text{ V},$ SREF1 = 1, SREF0 = 1 ⁽³⁾	3 V	0		μΑ		
I _{VEREF}	Static input current into VEREF-	0 V ≤ VEREF- ≤ V _{CC}	3 V		±1		μ A	

- (1) The external reference is used during conversion to charge and discharge the capacitance array. The input capacitance, C_I, is also the dynamic load for an external reference during conversion. The dynamic impedance of the reference supply should follow the recommendations on analog-source impedance to allow the charge to settle for 10-bit accuracy.
- (2) The accuracy limits the minimum positive external reference voltage. Lower reference voltage levels may be applied with reduced accuracy requirements.
- (3) Under this condition the external reference is internally buffered. The reference buffer is active and requires the reference buffer supply current I_{REFB}. The current consumption can be limited to the sample and conversion period with REBURST = 1.
- (4) The accuracy limits the maximum negative external reference voltage. Higher reference voltage levels may be applied with reduced accuracy requirements.
- (5) The accuracy limits the minimum external differential reference voltage. Lower differential reference voltage levels may be applied with reduced accuracy requirements.

10-Bit ADC, Timing Parameters (MSP430G2x53 Only)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITION	ONS	V _{CC}	MIN	TYP	MAX	UNIT
4	ADC10 input clock	For specified performance of	ADC10SR = 0	3 V	0.45		6.3	MHz
TADC10CLK	frequency	ADC10 linearity parameters	ADC10SR = 1	3 V	0.45		1.5	IVITIZ
f _{ADC10OSC}	ADC10 built-in oscillator frequency	ADC10DIVx = 0, ADC10SSELX fADC10CLK = fADC10OSC	3 V	3.7		6.3	MHz	
		ADC10 built-in oscillator, ADC1 fADC10CLK = fADC10OSC	3 V	2.06		3.51		
t _{CONVERT}	Conversion time	$f_{ADC10CLK}$ from ACLK, MCLK, or SMCLK: ADC10SSELx $\neq 0$				13 × C10DIV : ADC10CLK		μs
t _{ADC10ON}	Turn-on settling time of the ADC	(1)	·				100	ns

⁽¹⁾ The condition is that the error in a conversion started after t_{ADC10ON} is less than ±0.5 LSB. The reference and input signal are already settled.

10-Bit ADC, Linearity Parameters (MSP430G2x53 Only)

	3 117	_ 3 1 3 1	. `		,		
	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
E _I	Integral linearity error		3 V			±1	LSB
E _D	Differential linearity error		3 V			±1	LSB
Eo	Offset error	Source impedance R_S < 100 Ω	3 V			±1	LSB
E_G	Gain error		3 V		±1.1	±2	LSB
E _T	Total unadjusted error		3 V		±2	±5	LSB

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10-Bit ADC, Temperature Sensor and Built-In V_{MID} (MSP430G2x53 Only)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
I _{SENSOR}	Temperature sensor supply current ⁽¹⁾	REFON = 0, INCHx = 0Ah, $T_A = 25$ °C	3 V		60		μΑ
TC _{SENSOR}		ADC10ON = 1, INCHx = 0Ah (2)	3 V		3.55		mV/°C
t _{Sensor(sample)}	Sample time required if channel 10 is selected (3)	ADC10ON = 1, INCHx = 0Ah, Error of conversion result ≤ 1 LSB	3 V	30			μs
I _{VMID}	Current into divider at channel 11	ADC10ON = 1, INCHx = 0Bh	3 V			(4)	μΑ
V _{MID}	V _{CC} divider at channel 11	ADC10ON = 1, INCHx = 0Bh, $V_{MID} \neq 0.5 \times V_{CC}$	3 V		1.5		٧
t _{VMID(sample)}	Sample time required if channel 11 is selected ⁽⁵⁾	ADC10ON = 1, INCHx = 0Bh, Error of conversion result ≤ 1 LSB	3 V	1220			ns

⁽¹⁾ The sensor current I_{SENSOR} is consumed if (ADC10ON = 1 and REFON = 1) or (ADC10ON = 1 and INCH = 0Ah and sample signal is high). When REFON = 1, I_{SENSOR} is included in I_{REF+}. When REFON = 0, I_{SENSOR} applies during conversion of the temperature sensor input (INCH = 0Ah).

The following formula can be used to calculate the temperature sensor output voltage:

 $V_{Sensor,typ} = TC_{Sensor} (273 + T [^{\circ}C]) + V_{Offset,sensor} [mV] or$

 $V_{Sensor,typ} = TC_{Sensor} T [^{\circ}C] + V_{Sensor} (T_{A} = 0^{\circ}C) [mV]$ The typical equivalent impedance of the sensor is 51 k Ω . The sample time required includes the sensor-on time $t_{SENSOR(on)}$. No additional current is needed. The V_{MID} is used during sampling.

The on-time $t_{VMID(on)}$ is included in the sampling time $t_{VMID(sample)}$; no additional on time is needed.

Flash Memory

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
V _{CC(PGM/ERASE)}	Program and erase supply voltage			2.2		3.6	V
f _{FTG}	Flash timing generator frequency			257		476	kHz
I _{PGM}	Supply current from V _{CC} during program		2.2 V, 3.6 V		1	5	mA
I _{ERASE}	Supply current from V _{CC} during erase		2.2 V, 3.6 V		1	7	mA
t _{CPT}	Cumulative program time ⁽¹⁾		2.2 V, 3.6 V			10	ms
t _{CMErase}	Cumulative mass erase time		2.2 V, 3.6 V	20			ms
	Program/erase endurance			10 ⁴	10 ⁵		cycles
t _{Retention}	Data retention duration	T _J = 25°C		100			years
t _{Word}	Word or byte program time	(2)			30		t _{FTG}
t _{Block, 0}	Block program time for first byte or word	(2)			25		t _{FTG}
t _{Block, 1-63}	Block program time for each additional byte or word	(2)			18		t _{FTG}
t _{Block, End}	Block program end-sequence wait time	(2)			6		t _{FTG}
t _{Mass Erase}	Mass erase time	(2)			10593		t _{FTG}
t _{Seg Erase}	Segment erase time	(2)			4819		t _{FTG}

⁽¹⁾ The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.

These values are hardwired into the Flash Controller's state machine ($t_{FTG} = 1/f_{FTG}$).



RAM

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN MAX	UNIT
V _(RAMh)	RAM retention supply voltage (1)	CPU halted	1.6	V

⁽¹⁾ This parameter defines the minimum supply voltage V_{CC} when the data in RAM remains unchanged. No program execution should happen during this supply voltage condition.

JTAG and Spy-Bi-Wire Interface

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
f _{SBW}	Spy-Bi-Wire input frequency		2.2 V	0		20	MHz
t _{SBW,Low}	Spy-Bi-Wire low clock pulse duration		2.2 V	0.025		15	μs
t _{SBW,En}	Spy-Bi-Wire enable time (TEST high to acceptance of first clock edge ⁽¹⁾)		2.2 V			1	μs
t _{SBW,Ret}	Spy-Bi-Wire return to normal operation time		2.2 V	15		100	μs
f _{TCK}	TCK input frequency ⁽²⁾		2.2 V	0		5	MHz
R _{Internal}	Internal pulldown resistance on TEST		2.2 V	25	60	90	kΩ

⁽¹⁾ Tools accessing the Spy-Bi-Wire interface need to wait for the maximum t_{SBW,En} time after pulling the TEST/SBWTCK pin high before applying the first SBWTCK clock edge.

JTAG Fuse⁽¹⁾

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
V _{CC(FB)}	Supply voltage during fuse-blow condition	T _A = 25°C	2.5		V
V_{FB}	Voltage level on TEST for fuse blow		6	7	V
I _{FB}	Supply current into TEST during fuse blow			100	mA
t _{FB}	Time to blow fuse			1	ms

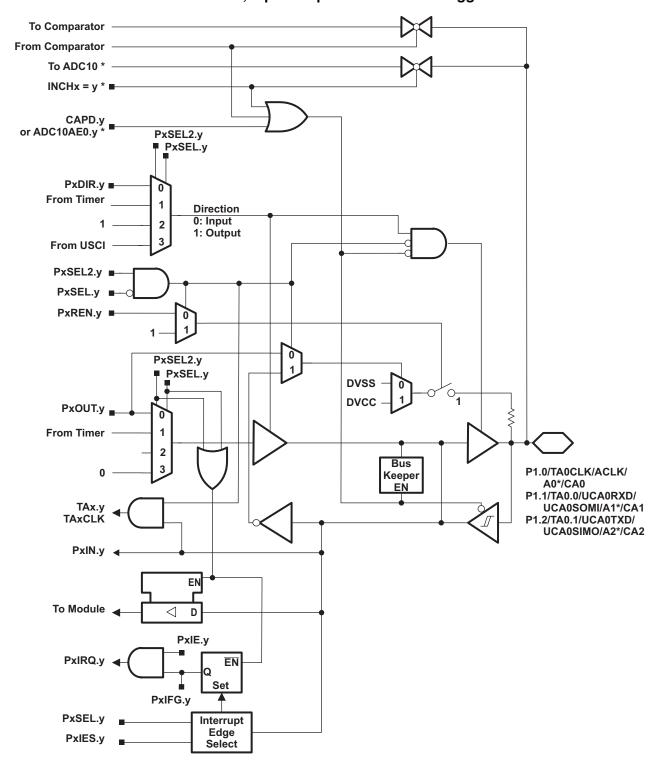
⁽¹⁾ Once the fuse is blown, no further access to the JTAG/Test, Spy-Bi-Wire, and emulation feature is possible, and JTAG is switched to bypass mode.

⁽²⁾ f_{TCK} may be restricted to meet the timing requirements of the module selected.



PORT SCHEMATICS

Port P1 Pin Schematic: P1.0 to P1.2, Input/Output With Schmitt Trigger



^{*} Note: MSP430G2x53 devices only. MSP430G2x13 devices have no ADC10.



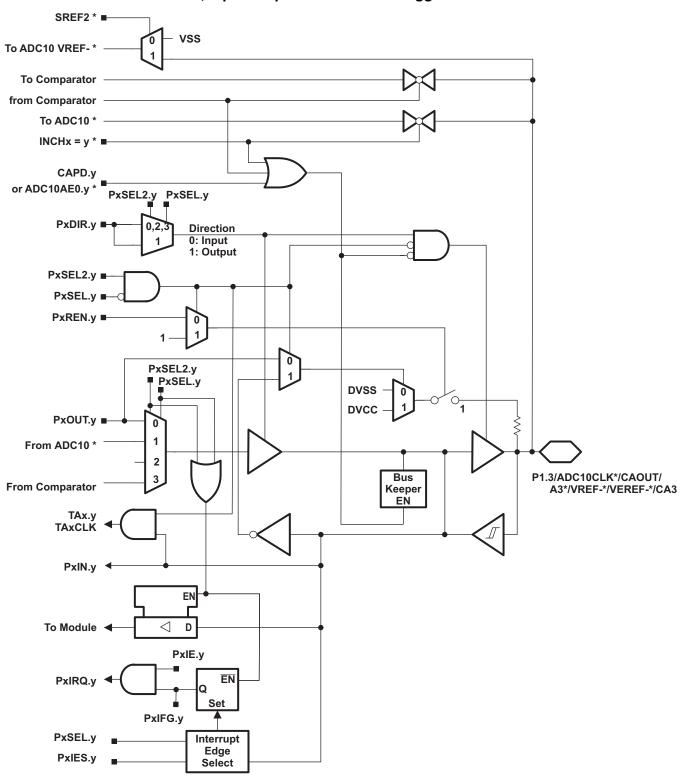
Table 16. Port P1 (P1.0 to P1.2) Pin Functions

DINI NIAME				CONTRO	OL BITS AND SIG	GNALS ⁽¹⁾	
PIN NAME (P1.x)	x	FUNCTION	P1DIR.x	P1SEL.x	P1SEL2.x	ADC10AE.x INCH.x=1 (2)	CAPD.y
P1.0/		P1.x (I/O)	I: 0; O: 1	0	0	0	0
TA0CLK/		TA0.TACLK	0	1	0	0	0
ACLK/	0	ACLK	1	1	0	0	0
A0 ⁽²⁾ /	U	A0	Х	Х	Х	1 (y = 0)	0
CA0/		CA0	Х	Х	Х	0	1 (y = 0)
Pin Osc		Capacitive sensing	Х	0	1	0	0
P1.1/		P1.x (I/O)	I: 0; O: 1	0	0	0	0
TA0.0/		TA0.0	1	1	0	0	0
		TA0.CCI0A	0	1	0	0	0
UCA0RXD/	1	UCA0RXD	from USCI	1	1	0	0
UCA0SOMI/	1	UCA0SOMI	from USCI	1	1	0	0
A1 ⁽²⁾ /		A1	X	Х	Х	1 (y = 1)	0
CA1/		CA1	Х	Х	Х	0	1 (y = 1)
Pin Osc		Capacitive sensing	Х	0	1	0	0
P1.2/		P1.x (I/O)	I: 0; O: 1	0	0	0	0
TA0.1/		TA0.1	1	1	0	0	0
		TA0.CCI1A	0	1	0	0	0
UCA0TXD/	2	UCA0TXD	from USCI	1	1	0	0
UCA0SIMO/	2	UCA0SIMO	from USCI	1	1	0	0
A2 ⁽²⁾ /		A2	Х	Х	Х	1 (y = 2)	0
CA2/		CA2	Х	Х	Х	0	1 (y = 2)
Pin Osc		Capacitive sensing	Х	0	1	0	0

⁽¹⁾ X = don't care(2) MSP430G2x53 devices only



Port P1 Pin Schematic: P1.3, Input/Output With Schmitt Trigger



^{*} Note: MSP430G2x53 devices only. MSP430G2x13 devices have no ADC10.



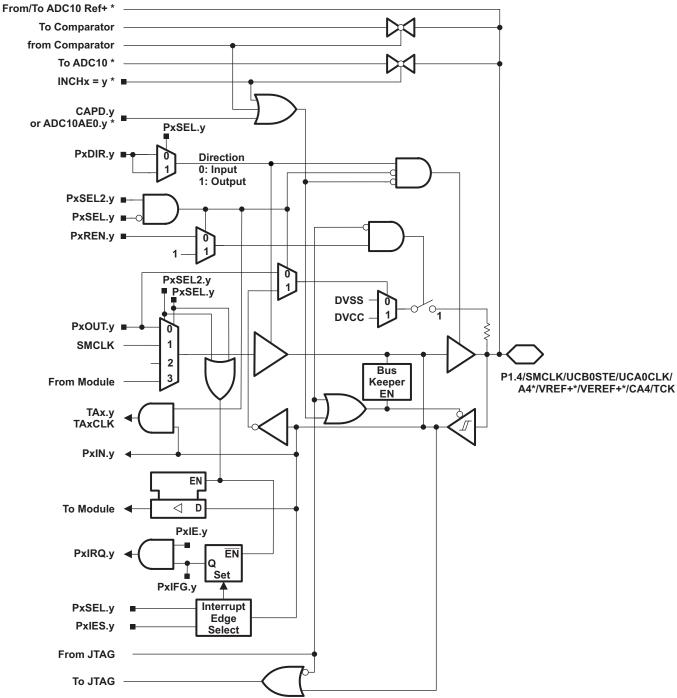
Table 17. Port P1 (P1.3) Pin Functions

DIN NAME				CONTRO	OL BITS AND SIG	GNALS ⁽¹⁾	
PIN NAME (P1.x)	x	FUNCTION	P1DIR.x	P1SEL.x	P1SEL2.x	ADC10AE.x INCH.x=1 (2)	CAPD.y
P1.3/		P1.x (I/O)	I: 0; O: 1	0	0	0	0
ADC10CLK ⁽²⁾ /		ADC10CLK	1	1	0	0	0
CAOUT/		CAOUT	1	1	1	0	0
A3 ⁽²⁾ /	3	A3	Х	Х	Х	1 (y = 3)	0
VREF-(2)/	3	VREF-	Х	Х	Х	1	0
VEREF-(2)/		VEREF-	Х	Х	Х	1	0
CA3/		CA3	Х	Х	Х	0	1 (y = 3)
Pin Osc		Capacitive sensing	Х	0	1	0	0

X = don't care MSP430G2x53 devices only



Port P1 Pin Schematic: P1.4, Input/Output With Schmitt Trigger



^{*} Note: MSP430G2x52 devices only. MSP430G2x12 devices have no ADC10.



Table 18. Port P1 (P1.4) Pin Functions

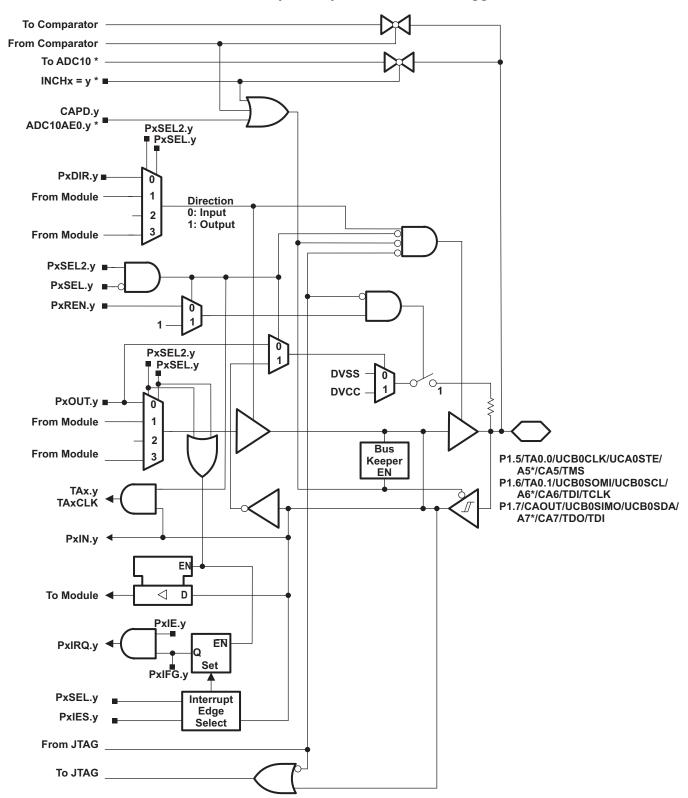
DINI NIAME					CONTROL BITS	AND SIGNALS(1)	
PIN NAME (P1.x)	x	FUNCTION	P1DIR.x	P1SEL.x	P1SEL2.x	ADC10AE.x INCH.x=1 (2)	JTAG Mode	CAPD.y
P1.4/		P1.x (I/O)	I: 0; O: 1	0	0	0	0	0
SMCLK/		SMCLK	1	1	0	0	0	0
UCB0STE/		UCB0STE	from USCI	1	1	0	0	0
UCA0CLK/		UCA0CLK	from USCI	1	1	0	0	0
VREF+(2)/		VREF+	Х	Х	Х	1	0	0
VEREF+(2)/	4	VEREF+	Х	Х	Х	1	0	0
A4 ⁽²⁾ /		A4	Х	Х	Х	1 (y = 4)	0	0
CA4		CA4	Х	Х	Х	0	0	1 (y = 4)
TCK/		TCK	Х	Х	Х	0	1	0
Pin Osc		Capacitive sensing	х	0	1	0	0	0

⁽¹⁾ X = don't care

⁽²⁾ MSP430G2x53 devices only



Port P1 Pin Schematic: P1.5 to P1.7, Input/Output With Schmitt Trigger



^{*} Note: MSP430G2x53 devices only. MSP430G2x13 devices have no ADC10.



Table 19. Port P1 (P1.5 to P1.7) Pin Functions

PIN NAME (P1.x)	x		CONTROL BITS AND SIGNALS ⁽¹⁾					
		FUNCTION	P1DIR.x	P1SEL.x	P1SEL2.x	ADC10AE.x INCH.x=1 (2)	JTAG Mode	CAPD.y
P1.5/		P1.x (I/O)	I: 0; O: 1	0	0	0	0	0
TA0.0/		TA0.0	1	1	0	0	0	0
UCB0CLK/		UCB0CLK	from USCI	1	1	0	0	0
UCA0STE/		UCA0STE	from USCI	1	1	0	0	0
A5 ⁽²⁾ /	5	A5	Х	Х	Х	1 (y = 5)	0	0
CA5		CA5	Х	Х	Х	0	0	1 (y = 5)
TMS		TMS	Х	Х	Х	0	1	0
Pin Osc		Capacitive sensing	х	0	1	0	0	0
P1.6/		P1.x (I/O)	I: 0; O: 1	0	0	0	0	0
ΓA0.1/		TA0.1	1	1	0	0	0	0
JCB0SOMI/		UCB0SOMI	from USCI	1	1	0	0	0
JCB0SCL/		UCB0SCL	from USCI	1	1	0	0	0
A6 ⁽²⁾ /	6	A6	Х	Х	Х	1 (y = 6)	0	0
CA6		CA6	Х	Х	Х	0	0	1 (y = 6)
TDI/TCLK/		TDI/TCLK	X	Х	Х	0	1	0
Pin Osc		Capacitive sensing	х	0	1	0	0	0
P1.7/		P1.x (I/O)	I: 0; O: 1	0	0	0	0	0
JCB0SIMO/		UCB0SIMO	from USCI	1	1	0	0	0
JCB0SDA/		UCB0SDA	from USCI	1	1	0	0	0
47 ⁽²⁾ /		A7	X	Х	Х	1 (y = 7)	0	0
CA7	7	CA7	Х	Х	Х	0	0	1 (y = 7)
CAOUT		CAOUT	1	1	0	0	0	0
ΓDO/TDI/		TDO/TDI	Х	Х	Х	0	1	0
Pin Osc		Capacitive sensing	Х	0	1	0	0	0

⁽¹⁾ X = don't care(2) MSP430G2x53 devices only



Port P2 Pin Schematic: P2.0 to P2.5, Input/Output With Schmitt Trigger

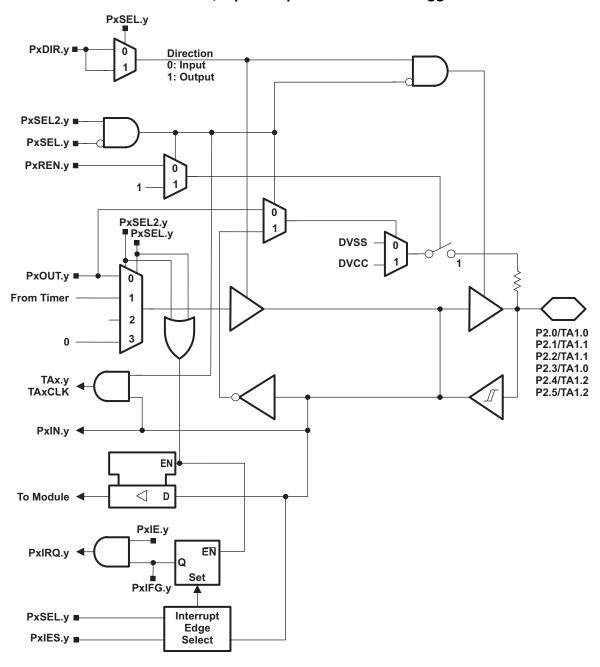




Table 20. Port P2 (P2.0 to P2.5) Pin Functions

PIN NAME	x	FUNCTION	CONTRO	CONTROL BITS AND SIGNALS ⁽¹⁾		
(P2.x)			P2DIR.x	P2SEL.x	P2SEL2.x	
P2.0/		P2.x (I/O)	I: 0; O: 1	0	0	
TA1.0/		Timer1_A3.CCI0A	0	1	0	
	0	Timer1_A3.TA0	1	1	0	
Pin Osc		Capacitive sensing	Х	0	1	
P2.1/		P2.x (I/O)	I: 0; O: 1	0	0	
TA1.1/	1	Timer1_A3.CCl1A	0	1	0	
	'	Timer1_A3.TA1	1	1	0	
Pin Osc		Capacitive sensing	X	0	1	
P2.2/		P2.x (I/O)	I: 0; O: 1	0	0	
TA1.1/	2	Timer1_A3.CCI1B	0	1	0	
	2	Timer1_A3.TA1	1	1	0	
Pin Osc		Capacitive sensing	X	0	1	
P2.3/		P2.x (I/O)	I: 0; O: 1	0	0	
TA1.0/	3	Timer1_A3.CCI0B	0	1	0	
	3	Timer1_A3.TA0	1	1	0	
Pin Osc		Capacitive sensing	X	0	1	
P2.4/		P2.x (I/O)	I: 0; O: 1	0	0	
TA1.2/	4	Timer1_A3.CCI2A	0	1	0	
	4	Timer1_A3.TA2	1	1	0	
Pin Osc		Capacitive sensing	X	0	1	
P2.5/		P2.x (I/O)	I: 0; O: 1	0	0	
TA1.2/	5	Timer1_A3.CCl2B	0	1	0	
	5	Timer1_A3.TA2	1	1	0	
Pin Osc		Capacitive sensing	X	0	1	

⁽¹⁾ X = don't care



Port P2 Pin Schematic: P2.6, Input/Output With Schmitt Trigger

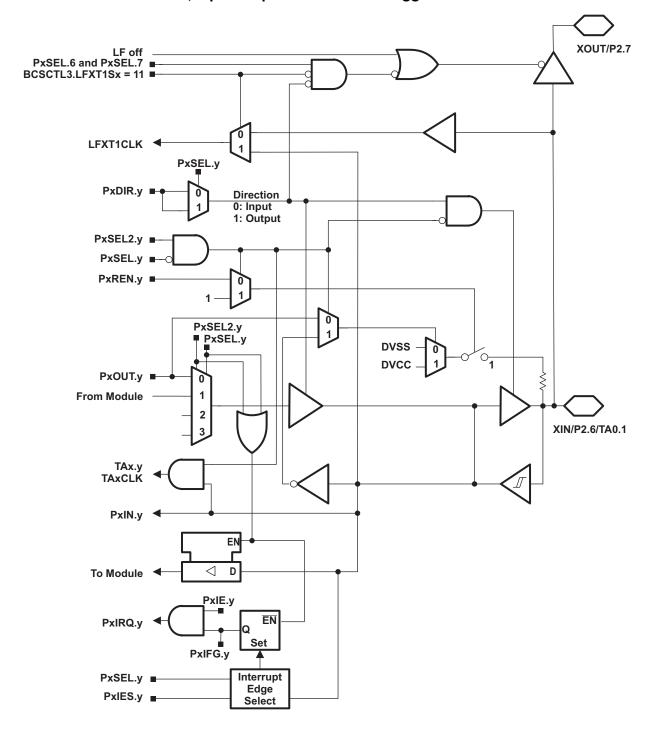




Table 21. Port P2 (P2.6) Pin Functions

PIN NAME	x	FUNCTION	CONTROL BITS AND SIGNALS ⁽¹⁾		
(P2.x)			P2DIR.x	P2SEL.6 P2SEL.7	P2SEL2.6 P2SEL2.7
XIN		XIN	0	1 1	0 0
P2.6	6	P2.x (I/O)	I: 0; O: 1	0 X	0 0
TA0.1	6	Timer0_A3.TA1	1	1 0	0 0
Pin Osc		Capacitive sensing	Х	0 X	1 X

⁽¹⁾ X = don't care



Port P2 Pin Schematic: P2.7, Input/Output With Schmitt Trigger

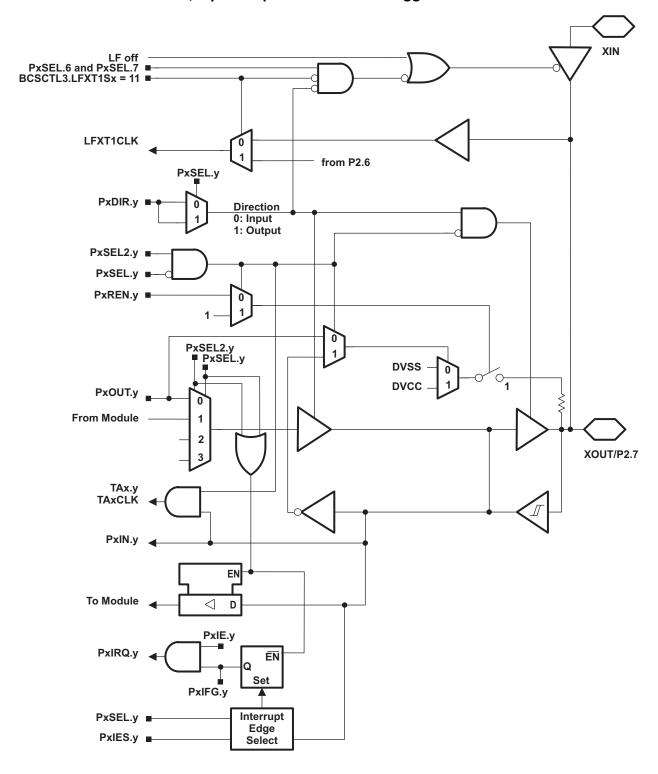




Table 22. Port P2 (P2.7) Pin Functions

PIN NAME	x	FUNCTION	CONTROL BITS AND SIGNALS ⁽¹⁾		
(P2.x)			P2DIR.x	P2SEL.6 P2SEL.7	P2SEL2.6 P2SEL2.7
XOUT/		XOUT	1	1 1	0
P2.7/	7	P2.x (I/O)	I: 0; O: 1	0 X	0 0
Pin Osc		Capacitive sensing	Х	0 X	1 X

(1) X = don't care



Port P3 Pin Schematic: P3.0 to P3.7, Input/Output With Schmitt Trigger (28-Pin PW and 32-Pin RHB Packages Only)

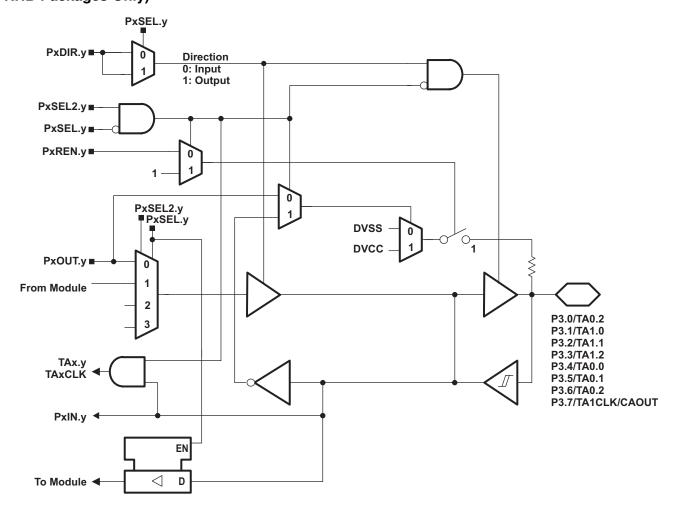




Table 23. Port P3 (P3.0 to P3.7) Pin Functions (28-Pin PW and 32-Pin RHB Packages Only)

PIN NAME		FUNCTION	CONTRO	CONTROL BITS AND SIGNALS ⁽¹⁾			
(P3.x)	x		P3DIR.x	P3SEL.x	P3SEL2.x		
P3.0/		P3.x (I/O)	I: 0; O: 1	0	0		
TA0.2/	0	Timer0_A3.CCl2A	0	1	0		
	0	Timer0_A3.TA2	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.1/		P3.x (I/O)	I: 0; O: 1	0	0		
TA1.0/	1	Timer1_A3.TA0	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.2/		P3.x (I/O)	I: 0; O: 1	0	0		
TA1.1/	2	Timer1_A3.TA1	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.3/		P3.x (I/O)	I: 0; O: 1	0	0		
TA1.2/	3	Timer1_A3.TA2	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.4/		P3.x (I/O)	I: 0; O: 1	0	0		
TA0.0/	4	Timer0_A3.TA0	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.5/		P3.x (I/O)	I: 0; O: 1	0	0		
TA0.1/	5	Timer0_A3.TA1	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.6/		P3.x (I/O)	I: 0; O: 1	0	0		
TA0.2/	6	Timer0_A3.TA2	1	1	0		
Pin Osc		Capacitive sensing	X	0	1		
P3.7/		P3.x (I/O)	I: 0; O: 1	0	0		
TA1CLK/	7	Timer1_A3.TACLK	0	1	0		
CAOUT/	'	Comparator output	1	1	0		
Pin Osc		Capacitive sensing	Х	0	1		

⁽¹⁾ X = don't care



REVISION HISTORY

REVISION	DESCRIPTION			
SLAS735	Initial release			
SLAS735A	Changed Control Bits / Signals column in Table 18 Changed Pin Name and Function columns in Table 23			
SLAS735B	Changed Storage temperature range limit in Absolute Maximum Ratings Added BSL functions to P1.1 and P1.5 in Table 2. Added CAOUT information to Table 17.			
SLAS735C	Changed T _{stg} , Programmed device, to -55°C to 150°C in Absolute Maximum Ratings. Changed TAG_ADC10_1 value to 0x10 in Table 10.			
SLAS735D	Added AVCC (RHB package only, pin 29) to Table 2 Terminal Functions. Corrected typo in P3.7/TA1CLK/CAOUT description in Table 2. Corrected PW28 terminal assignment in Input and Output Pin Number columns in Table 13. Changed all port schematics (added buffer after PxOUT.y mux) in Port Schematics.			
SLAS735E	Table 5 and Table 14, Corrected Timer_A register names.			
SLAS735F	Added note on TC _{REF+} in 10-Bit ADC, Built-In Voltage Reference (MSP430G2x53 Only). Corrected signal names on Port P1 Pin Schematic: P1.4, Input/Output With Schmitt Trigger.			
SLAS735G	Recommended Operating Conditions, Removed mention of USART module from f _{SYSTEM} description. Port P3 Pin Schematic: P3.0 to P3.7, Input/Output With Schmitt Trigger (28-Pin PW and 32-Pin RHB Packages Only), Added PW28 to available packages.			
SLAS735H	Recommended Operating Conditions, Added test conditions for typical values. Pin-Oscillator Frequency – Ports Px, Corrected resistor value in note (1). POR, BOR, Added note (2).			
SLAS735I	Throughout, Changed all variations of touch sense ⁽¹⁾ to capacitive touch.			
SLAS735J	Removed all information regarding MSP430G2113.			

⁽¹⁾ TouchSense is a trademark of Immersion Corporation.

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